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LENS INSPECTION SYSTEM AND METHOD

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(57) Claim

1. A system for inspecting ophthalmic lenses, comprising:

a transport subsystem for moving the lenses into an inspection position;

an illumination subsystem to generate a light beam and to direct the light beam through the lenses in the inspection position;

an imaging subsystem to generate a set of signals representing selected portions of the light beam transmitted through the lenses; and

an image processing subsystem to receive said signals from the imaging subsystem and to process said signals according to a predetermined program to identify at least one condition of each of said lenses;

wherein the illumination subsystem includes

i) a light source to generate the light beam,

ii) means to direct the light beam generally in a first direction and through lenses in the inspection position,

iii) a diffuser located in the path of the light beam to form the light beam with a generally uniform intensity across a transverse cross-section of the light beam,

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iv) a lens assembly to focus a portion of the light beam passing through the lenses onto an image plane, and to focus a portion of the light beam onto a focal point in front of the image plane to form a diffuse background pattern on the image plane.

5. A method for inspecting ophthalmic lenses, comprising:

moving the lenses into an inspection position;
generating a light beam;
generally directing the light beam in a first direction and through the lenses in the lens inspection position;

focusing a portion of the light beam passing through the lenses onto an image plane to form images of the lenses on said plane;

focusing a portion of the light beam onto a focal point in front of the image plane to form a diffuse background pattern on the image plane;

generating a set of signals representing the lens images formed on the image plane;

processing said signals according to a predetermined program to identify at least one condition of each of the lenses.

ABSTRACT

A system and method for inspecting ophthalmic lenses. The system (10) comprises a transport subsystem (12) for moving the lenses into an inspection position, and an illumination subsystem (14) to generate a light beam and to direct the light beam through the lenses. The system (10) further comprises an imaging subsystem (16) to generate a set of signals representing selected portions of the light beam transmitted through the lenses, and a processing subsystem (20) to process those signals according to a predetermined program. The illumination subsystem (14) includes a light source (36) to generate a light beam and a diffuser to form that light beam with a generally uniform intensity across the transverse cross section of the light beam. The illumination subsystem (14) further includes a lens assembly to focus a portion of the light beam onto an image plane, and to focus a portion of the light beam onto a focal point in front of the image plane to form a diffuser background pattern on the image plane.



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Invention Title: **LENS INSPECTION SYSTEM AND METHOD**

The following statement is a full description of this invention, including the best method of performing it known to us

LENS INSPECTION SYSTEM AND METHOD

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BACKGROUND OF THE INVENTION

This invention generally relates to systems for inspecting ophthalmic lenses, and more particularly, to
5 a high speed, automated system for inspecting contact lenses.

Recently, several automated systems have been developed for producing ophthalmic lenses, and in particular, contact lenses; and, for example, one such
10 system is disclosed in U.S. Patent 5,080,839. These systems have achieved a very high degree of automation; and, for instance, the lenses may be molded, removed from the molds, further processed, and packaged without any direct human involvement.

15 Moreover, in these automated systems, contact lenses are, typically, made with a high degree of precision and accuracy. Nevertheless, on rare occasions, a particular lens may contain some irregularity; and, for this reason, contact lenses are
20 inspected before sale to the consumer to be certain that the lenses are acceptable for consumer use.

Ophthalmic lenses may also be inspected automatically, and very reliable and accurate automated lens inspection systems are known. Some of these
25 automated systems tend to concentrate on inspecting the peripheries or outer portions of the lenses. It is thus believed that these systems could be improved by providing a procedure for better inspecting the center portions of the lenses.

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SUMMARY OF THE INVENTION

An object of this invention is to improve systems for inspecting ophthalmic lenses.

5 It may be desirable for the present invention to provide an automated lens inspection system with an illumination system that produces an image of a lens in which any defects in the center of the lens are enhanced.

10 It may be further desirable for this invention to produce an image of a contact lens in which the peripheral zone of the lens is visibly distinguishable.

The invention may also provide an automated system for inspecting contact lenses for very small irregularities in the centers of the lenses.

15 Accordingly, the invention provides a system for inspecting ophthalmic lenses, comprising:

a transport subsystem for moving the lenses into an inspection position;

20 an illumination subsystem to generate a light beam and to direct the light beam through the lenses in the inspection position;

an imaging subsystem to generate a set of signals representing selected portions of the light beam transmitted through the lenses; and

25 an image processing subsystem to receive said signals from the imaging subsystem and to process said signals according to a predetermined program to identify at least one condition of each of said lenses;

wherein the illumination subsystem includes

- 30 i) a light source to generate the light beam,
ii) means to direct the light beam generally in a first direction and through lenses in the inspection position,



iii) a diffuser located in the path of the light beam to form the light beam with a generally uniform intensity across a transverse cross-section of the light beam,

iv) a lens assembly to focus a portion of the light beam passing through the lenses onto an image plane, and to focus a portion of the light beam onto a focal point in front of the image plane to form a diffuse background pattern on the image plane.

In another aspect of the invention, there is provided a system for inspecting ophthalmic lenses, comprising

a lens holder for holding the lenses in an inspection position;

an array of pixels;

an illumination subsystem to generate a light beam and to direct the light beam through the lenses in the inspection position and onto the pixel array and including

i) a light source to generate the light beam,

ii) a diffuser located in a path of the light beam to diffuse the light beam, and located in series between the light source and the inspection position

In a further aspect of the invention, there is provided a method for inspecting ophthalmic lenses, comprising:

moving the lenses into an inspection position;

generating a light beam;

generally directing the light beam in a first direction and through the lenses in the lens inspection position;

focusing a portion of the light beam passing through the lenses onto an image plane to form images of the lenses on said plane;

focusing a portion of the light beam onto a focal point in front of the image plane to form a diffuse background pattern on the image plane;



generating a set of signals representing the lens images formed on the image plane;

processing said signals according to a predetermined program to identify at least one condition of each of the
5 lenses.

In another aspect of the invention, there is provided a method for inspecting ophthalmic lenses, comprising:

placing the lenses in an inspection position;

generating a light beam;

10 directing the light beam through the lenses and onto an array of pixels to form images of the lenses thereon;

locating a diffuser in a path of the light beam to diffuse the light beam;

15 positioning a doublet lens in the path of the light beam to focus a portion of the light beam onto a focal point forward of the pixel array;

positioning a field lens in the path of the light beam to focus a portion of the light beam passing through the lenses onto the pixel array;

20 generating a set of signals representing the lens images formed on the pixel array; and

processing said signals according to a predetermined program to identify at least one condition of each of the lenses.



BRIEF DESCRIPTION OF THE DRAWINGS

1 Figure 1 is a block diagram illustrating a lens inspection system embodying the present invention.

Figure 2 shows the illuminating and imaging subsystems of the inspection system shown in Figure 1.

5 Figure 3 is a plan view of an ophthalmic lens that may be inspected in the system of Figure 1.

Figure 4 is a side view of the ophthalmic lens of Figure 3.

10 Figure 4A is an enlarged view of a portion of an outer annulus of the ophthalmic lens.

Figure 5 is a top perspective view of a package that may be used to hold the ophthalmic lens.

Figure 6 is a side view of the package shown in Figure 5.

15 Figure 7 shows a pallet that may be used to carry a group of the package through the system of Figure 1.

Figure 8 schematically depicts a portion of a pixel array of the imaging subsystem, and the notation used to refer to the pixels of the array.

20 Figure 9 shows a cabinet housing various components of a processing subsystem of the inspection system of Figure 1.

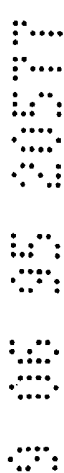
Figure 10 shows an image of a lens on a monitor of the inspection system.

25 Figure 11 illustrates a main window of a graphical user interface that may be used to transmit data to the processor means of the inspection system.

Figure 12 shows a graphical display window that may be used to transmit data to the processor means.

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1 Figure 13 outlines the major components of a preferred lens inspection process used with the inspection system of Figure 1.

Figures 14 and 15 show vectors that may be searched to find a lens in an image.

5 Figures 16A and 16B illustrate a pixel searching technique used in the preferred processing procedure.

Figures 17A and 17B show examples of lens searches that locate a noise object before locating the lens.

10 Figures 18 and 19 illustrate several features that may be used to determine whether a lens is badly torn.

15 Figure 20 schematically illustrates points on a lens edge that may be used to determine a model for that edge.

Figure 21 shows the concept of using radial deviation as a technique for determining angular tear spans for a lens.

20 Figure 22 shows graphically a technique for determining tear severity for a lens that has a discontinuous contour.

Figure 23 illustrates three windows that may be used to identify the junction between the peripheral and optical zones of a lens.

25 Figures 24 and 25 show two operators used to help identify the junction between the peripheral and optical zones.

30 Figure 26 illustrates a gradient histogram used to identify the junction between the peripheral and optical zones.

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1 Figure 27 shows a geometric relationship used in the decentration calculation.

Figure 28 shows the approximate location of the tick marks of a lens package, within an image.

5 Figure 29 shows a search region used to locate a first of the tic marks in an image.

Figure 30 shows search regions used to find additional tic marks.

10 Figure 31 illustrates search vectors that may be employed to identify a tic mark within a tic mark zone.

Figure 32 shows two regions in an image that may be used to adjust the grey levels of a tic mark.

Figure 33 illustrates how a tic mark is transformed.

15 Figure 34 illustrates the result of the transformation on a single row across a tic mark.

Figure 35 graphically illustrates the center zone region of a lens.

20 Figure 36 illustrates the pixel neighborhoods used for subsampling and gradient calculations.

Figure 37 shows a cross-section of a typical lens puddle.

Figure 38 graphically shows the peripheral zone of a lens.

25 Figure 39 shows the relationship between the gradient magnitude vector and the tangent direction vector.



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DETAILED DESCRIPTION OF THE PREFERRED EMBODIMENTS

1 Figure 1 illustrates lens inspection system 10;
and, generally, system 10 comprises transport subsystem
12, illumination subsystem 14, imaging subsystem 16 and
5 processing subsystem 20. Figure 1 also shows reject
mechanism 22, reject controller 24, and a plurality of
pallets 30, each of which holds a group of lens
packages.

With reference to Figures 1 and 2, preferably
10 transport subsystem 12 includes conveyor belt 32; and
illumination subsystem 14 includes housing 34, light
source 36, reflector 40, and lenses 42 and 44. Also,
with this preferred system 10, imaging subsystem 16
15 includes camera 46, and this camera, in turn, includes
housing 50, pixel array 52, shutter 54, and lens
assembly 56. Processing subsystem 20 includes image
processor means 60, operator interface means 62, and
supervisory computer 64; and, more specifically,
20 processor means includes a plurality of processor and
memory boards 60a, 60b, and 60c, and interface means
includes monitor 66 and host computer 70.

Generally, transport subsystem 12 is provided to
move a multitude of ophthalmic lenses along a
predetermined path and into a lens inspection system,
25 referenced at 72 in Figure 1. Illumination subsystem 14
is provided to generate a light beam and to direct that
beam through the lenses moving through the lens
inspection position. Subsystem 16 generates a set of
signals representing the light beam, or portions
thereof, transmitted through each inspected lens, and
30 then transmits those signals to processing subsystem 20.

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1 Subsystem 20 receives those signals from subsystem 16
and processes those signals according to a predetermined
program. For each inspected lens, subsystem 20
generates a signal indicating at least one condition of
the lens; and with the embodiment of subsystem 20
5 disclosed herein in detail, the subsystem generates a
signal indicating whether each inspected lens is
suitable for consumer use.

System 10 may be used to inspect a large variety
of types and sizes of ophthalmic lenses. The system is
10 particularly well suited for inspecting contact lenses,
and Figures 3 and 4 illustrate, for example, contact
lens 74 that may be inspected in system 10. Lens 74 has
a generally hollow, semi-spherical shape, including
front and back surfaces 76 and 80, and the lens forms a
15 central optical zone 74a and a peripheral zone 74b. The
lens has a substantially uniform thickness; however, as
particularly shown in Figure 4A, the thickness of the
lens gradually decreases over the annulus 74c
immediately adjacent the outside edge of the lens.

20 In the preferred operation of system 10, lenses
74 are located in individual packages or carriers, and
these carriers are held in pallets 30 that are
transported by conveyor 32 through the inspection
position 72. Various types of lens carriers and carrier
25 pallets may be used with system 20; and Figures 5 and 6
illustrate a carrier 82 that may be used to hold a lens
74, and Figure 7 shows a pallet 30 that may be used to
hold a group of packages 82.

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Carrier 82 includes a substantially planar first
1 surface 84, and formed within this planar first surface
is bowl or recess 86, which is concave when viewed from
the top of the carrier. A respective lens 74 is located
in cavity 86 of each carrier 82; and preferably, the
5 lens is fully submerged in a solution, such as deionized
water, in the carrier cavity. Preferably, the radius of
curvature, r , of cavity 86 is larger than the radius of
curvature of the ophthalmic lens 74 placed therein, so
10 that when a lens 74 is placed in a cavity 86, the
surfaces of the carrier 82 that form the cavity tend to
center the lens at the bottom of the cavity due to the
shape of the cavity.

Within the bowl 86 are contained a plurality of
15 ribs or tic marks 90 that are located near, but spaced
from, the center of the bowl. These tic marks may be
used to help hold lens 74 in recess 86 as deionized
water is removed from the recess. Preferably, the lens,
when centered in recess 86, does not make contact with
20 the tic marks, and instead the lens touches only the
center of the recess bottom at a point. With the
embodiment of carrier 82 shown in the drawings, each rib
90 is 0.5 mm long and 0.025 mm wide, and each rib is
located 3.0 mm from the center of bowl 86 and 6.0 mm
25 from the end of its collinear partner.

System 10 may be used independent of any specific
method or apparatus for placing or depositing lenses in
lens carriers 82. System 10 is well suited, though, for
30 use in a larger system in which lenses 74 are
automatically made, inspected, further processed, and

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1 then placed in carriers 82 by robots or automated lens
handling apparatus (not shown).

With reference to Figure 7, the embodiment of
pallet 30 shown therein is designed to hold a multitude
of packages or carriers 82 in two rows, and the pallet
5 may be provided with recesses or receptacles 30a for
receiving the carriers. With this arrangement, system
10 may be provided with two cameras 46, one to inspect
each row of packages 82 in pallets 30. Also, system may
be provided with additional inspection cameras; and, for
10 instance, the system may be provided with additional
cameras specifically used to inspect the peripheral
areas of lenses 74.

With reference again to Figure 1, conveyor belt
32 of transport subsystem 12 is mounted on a pair, or
15 more, of pulleys (not shown) that support the belt for
movement around an endless path. One of those pulleys
may be connected to a suitable drive means (not shown)
to rotate the pulley and, thereby, move the conveyor
belt around that endless path. Preferably, the drive
20 means is operated so that lenses 74 are moved through
system 10 in a smooth, continuous or substantially
continuous manner. Alternatively, though, lenses 74 may
be moved or indexed through system 10 in a discontinuous
or stepwise manner, and in particular, each lens may be
25 stopped for a brief period of time below imaging
subsystem 16.

More specifically, the preferred design of the
system 10 is such that groups of lenses are inspected in
cycles that correspond to pallet transfers. The
30 conveying system utilizes a mechanism, referred to as a

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1 walking beam mechanism, where pallets are pushed by an
arm attached to a linear slide. The slide extends to
move the pallet forward. Upon completing the slide's
stroke, its arm is retracted and the slide returns to
its starting position to begin another pallet transfer.
5 A complete pallet transfer occurs in three stages: a
start and acceleration stage, a constant velocity stage,
and a deceleration/stop stage. It is during this
constant velocity stage of movement that lenses are
under the cameras 46 and are being imaged. Preferably,
10 an entire cycle takes approximately twelve seconds, and
the resulting throughput is sixteen lenses approximately
every 12 seconds. Also, preferably, a single pallet
cycle begins with a pallet transfer, and the pallet is
at a constant velocity before reaching the camera 46 and
15 continues at that constant speed until all the lens
images have been captured.

In addition, any suitable ejector or reject
mechanism 22 may be employed in system 10. Preferably,
mechanism 22 is controlled by controller 24; and in
20 particular, when controller 24 receives a signal from
subsystem 20 that a lens is not suitable, the controller
actuates mechanism 22 to remove the package having that
lens from the stream of packages moving past the reject
mechanism. In the preferred operation of system 10, in
25 which lenses 74 are carried through the inspection
system by pallets 30, controller 24 operates mechanism
22 to remove only the packages having lenses that have
been determined to be unsuitable. Alternatively, a
reject mechanism may be used that removes a whole pallet
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from system 10 in case any lens in the pallet is found unsuitable.

5 With reference to Figures 1 and 2, subsystem 14 is used to generate a light beam 92 and to direct that beam through lenses 74 in inspection position 72. More specifically, light source 36 is disposed in housing 34, inside and adjacent the apex of parabolic reflector 40. The top of housing 34 is transparent and is preferably covered by a plate 94 of ground glass, and a doublet lens 42 and a field lens 44 are located in series between light source 36 and lens inspection position 72.

15 The preferred illuminating optics are designed for high contrast within the lens under test. To accomplish this, the two lenses 42 and 46 are used underneath the package. The purposes of these lenses are to condense the light and to compensate for the optical power created by the solution in cavity 86, as well as to enhance the optical contrast.

20 Lens 42 and 44 are positioned so that they form a lens assembly that focuses different portions of light beam 92 at different locations. In particular, this lens assembly focuses a portion of light beam 92 that passes through the ophthalmic lens 74 being tested, on to an image plane, specifically pixel array 52. This lens assembly also focuses a portion of light beam 92 onto a focal point, schematically referenced at 42a in Fig. 2, in front of the image plane to form a diffuse background pattern on the image plane.

30 In order to provide for the desired inspection of the center of lenses 74, the preferred illumination of the lens allows the whole center of the lens to be uniformly illuminated at grey levels in excess of 160, on a scale of 0 to 255. As discussed below, the camera sensor 52 is sensitive to grey levels ranging between 0 to 255. However,



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also as described in greater detail below, to enable the
desired inspection of the center of the lenses, the
peripheral zones of the lenses are a different grey level
than the back optic zone, in order to generate a detectable
5 boundary at the junction between the peripheral curve and the
back optical curve.

This boundary describes the inner circle of the



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1 peripheral zone and is used to test for decentration due
to misalignment of the back and front curve molds used
to mold the lens 74.

5 The light source 36 is preferably a strobe lamp
that is capable of producing, or firing, a five joule,
ten microsecond pulse of light, whenever image processor
60 generates a command signal, referred to as a grab
image command. A 450 millisecond recovery time is
preferably provided for the strobe lamp to recover
10 between firings of the light pulses.

15 The use of ground glass plate 94 affords higher
energies of illumination, since most of the light energy
remains unscattered from the pallet entrance pupil. A
relatively small amount of light is scattered out of the
optical path of the system, with most of the light
reaching the camera sensor 52.

20 Since the lens package 82 has a curve to form a
gravitational potential to center the lens in cavity 86,
the package acts as a lens within the imaging subsystem
16. For example, with an embodiment of the invention
that has actually been reduced to practice, package 82
acts as a lens with a focal length of 25 mm. Thus, the
light exiting package 82, if uncorrected, would
sufficiently diverge prior to entering the camera lens
56 so as to miss the camera aperture. This would tend
25 to underilluminate the image of the lens under test, and
reduce the available contrast in the image of the lens
produced on pixel array 52. To correct for this
divergence, field lens 44 is placed under the package 82
to counteract the optical power of the solution in the
30 package cavity 86.

1 With an embodiment of the invention that has been
actually reduced to practice, singlet lens 44 is from
Newport or Melles Griot, and is a -25 mm focal length
biconcave glass lens. It has a center thickness of 2.5
5 mm and a nominal edge thickness of 7.73 mm, and the
diameter of the singlet lens is 25.4 mm. A broadband
antireflection coating is applied to the lens to reduce
reflection and improve transmission through the lens,
thus enhancing contrast. The coating chosen is the
10 AR14, which is effective in the 430 to 700 nm wavelength
region.

The doublet lens 42 is the collector lens for the
illumination subsystem 14. The first focal point of
doublet lens 42 falls on the ground glass plate 94, in
15 order to approximately collimate the light transmitted
through the doublet lens. The doublet lens may be made
of ordinary BK-7 glass, although a fused silica lens can
be substituted without modification of the mechanical
mounts.

20 Imaging subsystem 16 receives the light beam
transmitted through the lens 74 in the inspection
position 72 and generates a series of signals
representing that light beam. With reference to Figures
1 and 2, pixel array 52 is disposed inside camera
housing 50, directly behind shutter 54. Pixel array 52
25 is preferably comprised of a multitude of light sensors,
each of which is capable of generating a respective
electric current having a magnitude proportional to or
representing the intensity of light incident on that
sensor. As is conventional, preferably the light
30 sensors, or pixels, of pixel array 52 are arranged in a

1 uniform grid of a given number of rows and columns, and
for example, that grid may consist of approximately one
million pixels arranged in approximately 1000 columns
and 1000 rows. Figure 8 schematically illustrates a
5 portion of a pixel array, and notation used herein to
refer to pixels of the array.

Preferably, the capability of the vision
subsystem 16 exceeds the resolution necessary to
classify all of the specified conditions for which
lenses 74 are inspected. For example, a camera may be
10 used that is capable of resolving 0.012 mm objects.
With 1,048,576 pixels in the imaged area, covering a
14.495 mm field of view, each pixel covers 0.01416 mm of
linear object space. Thus, a lens condition, such as an
15 extra piece or hole, covering exactly three pixels at
its largest diameter would be no more than 0.0425 mm in
size. Therefore, the vision system has the capability
of detecting conditions smaller than what is commonly
considered as the smallest flaw for which a lens may be
rejected.

20 In the operation of system 10, imaging camera 46
may be focused on the peripheral zones of lenses 74. In
this case, the center optical zones of lenses 74 are
also in focus, due to the depth of field of the imaging
lens. For example, the range of the field of view may
25 be selected to yield a 0.000055 mm per pixel variation
in pixel resolution, or a 0.057 millimeter total
variation in the field of view across the image.
Preferably, camera 46 is adjusted so that 989 pixels
equals 14.000 mm of object space. This results in the
30 above-mentioned single pixel resolution of 0.014156 mm



1 per pixel, or a field of view of 14.496 mm for the full
1024 pixels across the image.

As will be understood by those of ordinary skill
in the art, any suitable camera may be used in subsystem
16. With an embodiment of system 10 that has been
5 actually reduced to practice, camera 46 was a Class I
Kodak Megaplug high resolution camera with a Nikkor 55
mm standard lens. This camera has a 1320 by 1035 pixel
sensor, of which only 1024 by 1024 pixels were employed.
10 Since computer memory is binary in nature, and 1024
equals 2^{10} , then an area 2^{10} pixels by 2^{10} pixels, or
1,048,576 pixels, produces data that is easier to handle
within image memory from board level design
considerations.

15 The camera lens aperture was set at f/4 with a
field of view of 14.495 mm (lenses 74 in deionized water
may be about 12.2 mm in diameter). Attached to the end
of the camera lens was an Andover bandpass filter
centered at a wavelength of 550 nm, with a 10 nm full
20 wave half height window. Such a filter removes all
possibility of chromatic aberrations, improves overall
spatial resolution, and maintains a photopic response to
the lens inspection similar to an inspector's ocular
response. It also removes infrared light at the CCD
25 detector. This is advantageous since such light would
decrease the overall system modulation transfer
function.

Processing subsystem 20 receives the signals from
imaging subsystem 16, specifically pixel array 52, and
30 processes those signals, according to a predetermined
program discussed below in detail, to identify at least

1 one condition of the inspected lenses. More
specifically, the electric signals from the pixel array
52 of camera 42 are conducted to image processor means
60. The processor means 60 converts each electric
5 current signal from each pixel of array 52 into a
respective one digital data value, and stores that data
value at a memory location having an address associated
with the address of the pixel that generated the
electric signal.

10 Preferably, subsystem 20 is also employed to
coordinate or control the operation of subsystems 14 and
16 so that light source 36 is actuated and camera 46 is
operated in coordination with movement of lenses 74
through system 10. To elaborate, as the pallet enters
15 the inspection area, a pallet sensor detects its
presence. Upon receiving this signal, image processor
60 completes any ongoing processes from the previous
pallet and then reports those results, preferably to
both the PLC controller and the supervisory computer.

20 As the pallet continues moving along the conveyor, a
package sensor detects a package and generates a signal.
This signal indicates that a lens is in the proper
position to be imaged.

25 Upon receiving a package detect signal, the image
processing hardware initiates an image capture and
processes the image to the point where a pass/fail
decision is made. As part of the image capture, a
strobe is also fired to irradiate the lens. Lens
pass/fail information is stored until the start of the
next pallet, at which time results are reported. If a
30 report is not received --which might happen, for

1 example, if a sensor does not properly detect a pallet--
then no further pallet transfers are allowed. The
package detect sensor signals a detect for each of the
eight packages found on each side of the pallet.

5 Even more specifically, the image processing
boards determine when to image the lenses. Using fiber
optic sensors, as the pallet traverses below the camera,
each package edge is detected. Upon the detection of
each package edge, the strobe fires, and the camera
10 images the contact lens. The image acquisition is
initiated by the image processing board by transmitting
a grab signal to the camera. After the strobe firing,
the stored image is transferred into the memory of one
of the processor boards --referred to as the master
15 processor-- from the memory of the camera. The group
master processor determines which of the other two
processor boards --referred to as the slave processors--
are free to inspect the image currently being received.
The master processor directs where the image should be
20 processed, informing the slave processors which of them
should acquire the image data from the video bus. The
master processor also monitors the inspection and final
results for each image.

After processing a lens image and inspecting for
center defects, the two slave processors report to the
25 master processor. The master processor collects this
information and then transmits two reports. One report
goes to the PLC controlling the motion of the
Accept/Reject Robot. It determines the adjudication of
each package on the pallet just inspected. The PLC
30 tracks the pallets on a first in, first out manner. The

1 second report goes out to the supervisory computer for
passive data collection and analysis by manufacturing
control programs and production schedulers.

Any appropriate processing units may be employed
in system 10; and, for instance, the processing units
5 60a, 60b, and 60c may be IP-940 image processor machine
vision boards sold by Perceptics Corp.

Host computer 70, which preferably includes a
keyboard 70a and a video terminal 70b, is connected to
processor means 60 to display visually data or messages
10 being input into the processor. Monitor 66 is also
connected to processor means 60 and is provided to
produce video images from the data values stored in the
processor means, and monitor 66 may also be used to
display inspection results and totals. Preferably,
15 monitor 66 is a high resolution color monitor and is
controlled by a Perceptics high resolution display card,
the HRD900, which is also connected to image boards 60a,
60b, and 60c. RS232 connectors on the processor boards
allow terminal 66 to interact with the processor boards.
20

More specifically, the system's operator
interface is accomplished through Sun host computer 70
and high-resolution monitors 66. The Sun host computer
allows connection and communication to the processor
boards. The keyboard of the host computer is used to
25 input information to the processor boards and video
displays, of the type referred to as windows, on the
monitor of the host computer displays results and
status messages. The high-resolution monitors display
those images captured during operation. Status and
30

1 results information are also displayed on the high-
resolution monitors.

With reference to Figure 10, each time a lens is
imaged, it will briefly appear on the high resolution
monitor, along with an inspection report for the entire
5 pallet. Any error messages, as necessary, may also
appear on the high resolution display. The image on the
high resolution monitor is broadcast by the high
resolution display board, or HRD. This board controls
the video bus. It acquires the images from the IP-940
10 image processor boards and displays either the edge or
center image, from the edge or center cameras,
respectively, as selected by an operator. Essentially,
the HRD board monitors the images as they are processed,
and displays them in real time on the monitor, without
15 interfering in the processing of the images.

A graphical user interface may be used to
transmit commands and data from an operator to processor
means 60. Figure 11 shows a main window of a graphical
user interface, a single screen control mechanism for
20 the processor boards in the system. Preferably, this
screen is brought up by entering one command,
machinename% ipmgr&, at the host, preferably Sun,
command prompt. From this screen terminal, windows can
be added or subtracted from the host computer window
25 environment. By selecting the "terminals" button at the
top of the ipmgr window, a new window appears, as shown
in Figure 12. This window allows the operator to open a
host window for each of the image processor boards.
Opening each terminal window is like connecting a dumb
30 terminal to each of the processor boards selected. They

1 may be used for pallet Pass/Fail reports and for
debugging or experimental situations.

As will be understood, subsystem 20 may be
provided with other or additional input and output
5 devices to allow an operator or analyst to interact with
processor boards and controller 24. For example, a
printer may be connected to the processor boards to
provide a printed record of selected data values or
reports transmitted to the printed from the processor
board.

10 Preferably, a printout may be obtained by any of
several methods via the host operating system. The
screen reports from the master processor may be printed
by saving the screen information to a file, and then
printing it out at a later time. Also, the printer
15 could be used to print information as it scrolls off of
the screen. All of the information on lens disposition
is sent concurrently to the supervisory computer, which
preferably can assimilate the data and output production
reports.

20 With reference to Figure 9, all image processing
hardware, the host computer, monitors, and an
uninterruptable power supply are preferably housed in a
single cabinet. All cabling found in the system that
eventually becomes external to the cabinet first passes
25 through a bulkhead plate.

As discussed above, each time a lens 74 passes
through inspection position 72, light is transmitted
through the lens and onto pixel array 52, and the pixels
of the array generate electric currents representing the
30 intensity of the light on the pixels. These currents

1 are converted to digital data values that are stored in
processor means 60, and these data values are then
processed, preferably to determine if the lens is
suitable for consumer use. The preferred embodiment of
5 the inspection process detects missing lenses, edge
chips, edge tears, surface tears, excess pieces, holes,
puddles, decentration, and rust, and the process
analyzes these features to determine if the lens should
be rejected.

10 Figure 13 shows the major steps of a preferred
lens inspection process. The first steps in this
process are to locate the lens in the image on the pixel
array, to test for a badly torn lens, and to model the
outer edge of the lens. If a lens fails at any one of
15 these three steps, then the lens may be automatically
rejected. If the lens passes these first three steps,
the algorithm determines the lens decentration,
processes the package tick marks, and searches for flaws
in the peripheral zone and then in the center zone of
20 the lens. If any flaws are detected during these latter
steps, then the algorithm determines whether the lens is
acceptable or should be rejected.

Locate Lens in Image

25 The initial step in the lens inspection process,
subsequent to input of the raw image, is to determine
the location of the lens within the field of view. One
difficulty with prior art procedures is the
misclassification of badly torn or fragmented lenses as
missing lenses. Classification of a lens fragment as a
30 missing lens may cause difficulties in case the
deionized water is removed from carrier cavity 86 after

1 the lens inspection. For example, if a large lens
fragment is never recognized in cavity 86, that lens
fragment might clog an exit vent in a water removal
nozzle, diminishing transfer efficiency.

5 System 10 solves this problem because it not only
finds lenses, but also finds fragments of lenses, and
classifies them as fragments in order that the packages
containing them can be manually handled. If a large
lens fragment is located within a package, the
10 inspection system signals the controlling PLC 24 to stop
the transport subsystem 12 and alerts an operator to
remove the lens fragment from the package.

15 Generally, the image formed on pixel array 52 is
searched for image objects, which could be images of
lenses or fragments, by using horizontal and vertical
search vectors. The search vectors analyze the image
gradients according to equation (1).

$$G = |(P_{i-1,j+1} + 2P_{i,j+1} + P_{i+1,j+1}) - (P_{i-1,j-1} + 2P_{i,j-1} + P_{i+1,j-1})| \quad (1) \\ + |(P_{i-1,j+1} + 2P_{i-1,j} + P_{i-1,j-1}) - (P_{i+1,j+1} + 2P_{i+1,j} + P_{i+1,j-1})|$$

20 The gradient, G, is calculated for each pixel
along the search vector. If the calculated gradient
magnitude meets or exceeds a specified threshold,
25 defined by a parameter "E_findThr," a lens has
potentially been found. Equation (1) is formed by the
taking the absolute values of the x and y Sobel
operators. Unlike the usual operation involving total
image convolution, this modified Sobel only marches
30 along the search vector direction. Also the gradient

magnitude, G , is all that equation (1) determines. It is insensitive to the direction, or the sign, of the gradient. This makes the detection of edges more sensitive, in that both positive and negative edge gradients may be detected. Moreover, equation (1) may be used for both the horizontal and vertical edge detection search vectors. The edge detection search vectors preferably cover at least 50% of the image area.

More specifically, with reference to Figures 14 and 15, preferably a series of ten horizontal and ten vertical search vectors are potentially traversed. These vectors are spaced apart equal distances from each other and the location of all vectors is such that they avoid the dark areas found in the four corners of an image. The order in which search vectors are traversed is shown in Figures 14 and 15. Direction is indicated by the arrows and order is indicated by the number next to the vector.

These vectors are searched according to this predefined order until a lens is located or until all vectors have been traversed. If a lens is located, preferably no further searching is performed along the search vectors. A normal lens, for example, may be found while searching along the first search vector, while it may be necessary to search along most of the search vectors in order to find a badly torn lens.

After initially locating an object, a secondary test is conducted to verify lens detection. This verification test tracks the contour of the object just found. Any suitable connectivity procedure may be used to do this, and for instance, the edges may be tracked



1 using a technique that may be referred to as eight
connectivity analysis. In this technique, when a first
pixel is found that is on an edge of a particular
object, the eight immediate pixel neighbors of that
5 pixel are searched, in a uniform direction, for a second
edge pixel. If a second edge pixel is found, it is
considered to be on the edge of the particular object,
and, also, the process is repeated and the eight
immediate neighbors of this second edge pixel are
10 searched, in the uniform direction, for a third edge
pixel. This process is repeated --a procedure referred
to as tracking the edge or tracking the object-- until
an end of the edge is found, a predetermined number of
edge pixels are encountered before the edge returns to
15 its original pixel, or the edge formed by these
identified edge pixels forms a closed loop, and more
specifically, that edge returns to the first edge pixel
of the particular object.

Figures 16A and 16B illustrate this eight
connectivity analysis in greater detail. In Figures 16A
20 and 16B, each pixel is represented by a point, to better
illustrate the search around each pixel. Figure 16A
shows a first pixel, $P_{1,j}$, that has been identified as
being on an object edge. The eight immediate pixel
neighbors are searched, in a counterclockwise direction
25 starting from the pixel immediately above $P_{1,j}$, for a
pixel that has a grey level above a predetermined
threshold. The first pixel that is found that meets
this test is considered as the next edge pixel, which in
the example of Figure 16A is pixel $P_{1,j+1}$.



1 At the next step, illustrated in Figure 16B, the
eight immediate pixel neighbors of $P_{i,j+1}$ are searched
--again, in a counterclockwise direction starting from
the pixel immediately above $P_{i,j+1}$ -- for a pixel that
(i) has a grey level above the predetermined threshold,
5 and (ii) was not the pixel at the center of the
immediately preceding search. The first pixel that is
found that meets this test is considered as the next
edge pixel; and in the example shown in Figure 16B, that
next edge pixel is $P_{i,j+2}$. This tracking process
10 continues until the search returns to pixel $P_{i,j}$, a
predetermined number of contour pixels have been
encountered before the contour returns to its starting
location, or a search around a given pixel fails to
identify any next edge pixel.

15 Preferably, gradient magnitude is used during
this tracking procedure to determine those pixels on and
external to the object's contour. Calculation of
gradient magnitude is identical to that used by the
search vector routines and is defined by Equation (1).
20 The threshold value used during this tracking is also
identical to the one used by the search vectors and is
specified by the parameter "E_findThr."

If, during tracking of the object, its contour
starting location is not encountered before a specified
25 number of contour pixels have been tracked, a lens
object is considered verified. If, however, the
starting location is encountered before that specified
number of contour pixels is reached, the object is not
considered to be a lens, and is referred to as noise.
30 The minimum lens contour length used during this



1 verification test is given by the parameter
"B_cont_cnt." If a noise object is encountered while
searching along one vector, no further searching is
performed along that one vector, and processing
5 continues on the next search vector. This procedure is
repeated until a lens has been found or until all search
vectors have been tried. Figure 17A shows an example of
a hypothetical lens detect search that finds a noise
object before locating the lens, and Figure 17B shows an
10 example of a hypothetical lens detect search that finds
two noise objects before locating a badly torn lens.

If a lens is not found after trying all search
vectors, the lens is determined to be missing. This
result is reported and further processing is aborted.
15 If a lens is found, the image coordinates that
originally detected the lens are retained and further
processing is continued.

Two further tests may be performed before the
morphological features of the object are analyzed to
20 determine if the object is a badly torn lens. First, if
while tracking around the object, tracking runs off the
outer boundary of the image memory, then the lens
candidate is partially out of the field of view and the
lens candidate is failed. In this case no further
processing is attempted or performed on the image.
25 Second, if while tracking around the object, a maximum
number of contour pixels is exceeded, then the lens
candidate is too large to be a single lens and the lens
candidate is failed.



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Test for Fragmented or Badly Torn Lens

1 Thus, at this point, if processing is to
continue, the lens candidate is either a badly torn lens
or a whole lens. If the starting location of a lens
candidate is encountered during tracking, then the
5 object is considered to have been traversed along its
entire outer dimension. The morphological tests for a
badly torn lens are triggered, or initiated, by either
the condition of encountering the starting pixel, or the
10 condition of exceeding the maximum number of contour
pixels.

The preferred embodiment of the algorithm employs
two main tests, referred to as elongation and bounding
box size, to determine if an object is a badly torn
lens. The elongation test is primarily designed to
15 identify lenses having large segments removed or
missing, so that the lens no longer approximates a
circular object with a unitary eccentricity. The
bounding box test provides a check on the elongation
test, and in particular, is used to identify badly torn
20 lenses that are somewhat circular.

Both of the above-discussed tests use coordinate
information obtained from tracking the entire contour of
the lens. The tracking technique is identical to that
used to verify lens detection. The tracking process
25 uses gradient magnitude, as defined in Equation (1), to
determine if a pixel is on or external to the lens
contour. Eight connectivity analysis is used to track
along the lens contour, and the gradient magnitude
threshold is specified by the parameter "C_findThr."
30

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1 As tracking is performed, a sequential record of
the row and column locations of each pixel in the
contour is maintained. Contour tracking continues until
one of three events occurs: 1) tracking runs off image
memory, 2) the maximum allowable number of contour
5 pixels is exceeded, or 3) the starting location of the
lens contour is encountered.

If tracking runs off image memory, the lens is
considered to be partially outside the image field of
view and the lens is failed. The result is reported and
10 further processing is aborted. If the starting location
of the lens is encountered, or if the maximum allowable
number of contour pixels is exceeded, then the
morphological features referred to as elongation and
boundary area or bounding box are extracted to determine
15 if a badly torn lens is present.

The elongation value of an object is given by
Equation (2):

20
$$Elongation = \left[\frac{\text{moment of inertia about principal axis}}{\text{moment of inertia about minor axis}} \right] \quad (2)$$

The elongation test also provides a measure of an
object's maximum moment of inertia divided by its
25 minimum moment of inertia. The more disproportionate
the longest to shortest dimensions of an object, the
larger the elongation value; and the more compact an
object, the smaller its elongation value. For example,
30 a circle shaped object has the smallest theoretical

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1 elongation value, while a rod or line-shaped object
would have a relatively large elongation value.

In order to calculate elongation, a pass is made
over the coordinate data for all contour pixels. From
this pass, horizontal and vertical moments of inertia
5 are calculated. Equations (3) and (4) show the
calculations involved for these moments.

vertical moment of inertia = $\text{abs}(\sum (x_i - x_{avg})^2)$
10 = $\text{abs}(\sum x_i^2 - (\sum x_i)^2 / \text{contour count})$ (3)

where;

x_i = the column coordinate of the i^{th} pixel found
along the lens' outer contour. Summation occurs over
all pixels found on the lens' contour.

15 x_{avg} = the object's column centroid

horizontal moment of inertia = $\text{abs}(\sum (y_i - y_{avg})^2)$
= $\text{abs}(\sum y_i^2 - (\sum y_i)^2 / \text{contour count})$ (4)

where;

20 y_i = the row coordinate of the i^{th} pixel found along
the lens' outer contour. Summation occurs over
all pixels found on the lens' contour.

y_{avg} = the object's row centroid

From these two pieces of information, the angle
at which the object's principal axis lies can be found.

25 This is detailed in Equation (5).

$\phi = \arctan((2 * \sum (x_i - x_{avg})(y_i - y_{avg})) /$
 $(\sum (x_i - x_{avg})^2 - (y_i - y_{avg})^2)) / 2$ (5)

where;

30 ϕ = the angle, with respect to the object centroid, at
which the principal axis lies

35



1 With the angle of the principal axis determined,
 a final pass is made over the coordinate data for all
 contour pixels to calculate, for each such pixel,
 inertia about the principal and minor axes. Equations
 5 (6) and (7) detail these calculations.

moment of inertia about
 principal axis

$$= \text{abs}(\sum ((-x_i \sin(\phi) + y_i \cos(\phi)) - x'_{\text{avg}})^2)$$

$$= \text{abs}(\sum (-x_i \sin(\phi) + y_i \cos(\phi))^2 -$$

10 $(\sum (-x_i \sin(\phi) + y_i \cos(\phi)))^2 /$ (6)
 contour count))

where;

15 x_i = the column coordinate of the i^{th} pixel found
 along the lens' outer contour. Summation
 occurs over all pixels found on the lens'
 contour.

y_i = the row coordinate of the i^{th} pixel found along
 the lens' outer contour. Summation occurs over
 all pixels found on the lens' contour.

20 x'_{avg} = the object's centroid along the principal axis.

moment of inertia about
 minor axis

$$= \text{abs}(\sum ((x_i \cos(\phi) + y_i \sin(\phi)) - y'_{\text{avg}})^2)$$

$$= \text{abs}(\sum (x_i \cos(\phi) + y_i \sin(\phi))^2 -$$

25 $(\sum (x_i \cos(\phi) + y_i \sin(\phi)))^2 /$ (7)
 contour count))

where;

30 x_i = the column coordinate of the i^{th} pixel found
 along the lens' outer contour. Summation
 occurs over all pixels found on the lens'
 contour.

35



1 y_i = the row coordinate of the i^{th} pixel found along
 the lens' outer contour. Summation occurs over
 all pixels found on the lens' contour.

y'_{avg} = the object' s centroid along the minor axis.

5 Elongation is then calculated as described in
 Equation (2). The calculated elongation value is
 compared to the value specified by the parameter
 "C_elong" to determine if the lens is badly torn or not.
10 If, for example, that calculated elongation value is
 greater than "C_elong," then the lens is considered
 badly torn and is failed, and further processing is
 aborted.

 Figure 18 shows some of the terminology involved
 with the elongation feature.

15 A bounding box feature is also calculated for the
 lens object. Generally, the bounding box is a box just
 large enough to hold the lens candidate based upon the
 maximum and minimum vertical and horizontal axes of the
 object. It has been found that such a box serves as a
20 close approximation to the actual object area of the
 lens candidate. This test is employed to identify badly
 torn lenses that might not be identified by the
 elongation test. To elaborate, a badly torn lens could
 be so distorted that it could actually appear somewhat
25 circular, and thus not be identified by the elongation
 test. The bounding box test utilizes the characteristic
 that a badly torn but somewhat circular lens, is
 substantially smaller than a normal size lens. The box
 is oriented along horizontal and vertical axes which
30 pass through the object's centroid. Figure 19 shows the



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1 concept of the bounding box test, and Equation (8)
defines this test.

$$\begin{aligned} \text{Bounding Box} &= (\text{right most column in object} - \text{left most column in object}) \quad (8) \\ &\quad * (\text{bottom most row in object} - \text{top most row in object}) \end{aligned}$$

5
The calculated bounding box value is compared to the value specified by the parameter "C_bdbbox." If, for example, that calculated value is less than "C_bdbbox," then the lens is considered badly torn and is failed,
10 and further processing is aborted.

Model Lens Outer Edge

If the lens candidate passes both the elongation and bounding box size requirements, then a second
15 technique for detection of badly torn lenses is performed. With reference to Figure 20, six circular models are defined from the object tracking data, using six data points on the object edge and approximately 60 degrees apart. Each set of three consecutive data
20 points is used to define a unique circle. The sets are data points {1,2,3}, {2,3,4}, {3,4,5}, {4,5,6}, {5,6,1}, and {6,1,2}. The circular model having the radius that most closely matches the radius defined by the parameter B_lens_dia, is used as the lens outer edge model.

25 Preferably, for each circular model, the data points used to define the circle are first checked to ensure that they are not too close to each other. It is possible for this to occur if a lens contains a tear that prevents the contour from being continuous for the entire 360 degrees of a lens. A data set that contains
30 data points that are too close to each other may



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1 inadvertently result in an erroneous model and is,
preferably, ignored.

Each pixel along the contour of the lens
candidate is compared to the theoretical model used as
the lens edge. Using a rectangular to polar coordinate
5 look up table, each contour pixel is restated by using
radius and angular displacement around the edge. If the
value for the radius to any pixel is less than 90% of
the radius of the circular model used as the lens edge,
10 then the pixel is considered to be part of a large tear.
Each group of pixels considered to be part of a common
tear are measured in units of degrees. If the start and
stop points of the tear demonstrate that the tear is
larger than the parameter C_badtear, then the lens is
15 considered badly torn and failed. Figure 21 illustrates
the concept of using radial deviation as a technique for
determining tear spans for a lens.

In the event the contour of the lens is not
continuous all the way around the lens, the algorithm
20 marks the start and stop points of a tear by determining
when the tracking along that contour reverses directions
--a condition referred to as doubling back. When a
first doubling back condition is sensed, that location
is marked as the starting point of a tear. At this
25 point, tracking has reversed directions and is following
the inner side of the lens contour. Since it is not
possible to reencounter the original discontinuity point
from the other side of the lens, it can be inferred that
the next doubling back condition detected is the
30 opposite side of the tear that is causing the
discontinuity.



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1 This technique is used to solve the problem of
determining the severity of a tear in a lens that has a
discontinuous contour. Figure 22 shows graphically the
concept involved with this portion of the algorithm. If
5 a discontinuity occurs within a tear, the span of the
tear is adjusted to include the portion of the lens
between the point at which the tear began and the
discontinuity. This produces a more accurate
representation of tear severity.

10 If a lens has not been failed for running off the
image memory space during tracking, or for exceeding the
maximum number of contour pixels, elongation, or
bounding box size limits, the lens is considered to be
whole. As Figure 13 shows, the lens has not yet been
15 classified as passed, but at this point the lens has
been found and identified to be of acceptable quality
for further processing of the inspection image. The
next step is to test for decentration.

Decentration

20 A lens with a decentration that allows for a
peripheral zone width of, for example, 0.270 mm or
smaller may be deemed to be unacceptable. Since the
lenses are inspected in deionized water instead of the
saline packing solution, the lenses have not yet
25 expanded to their full and ultimate size. As a first
approximation, the peripheral zone can be considered as
part of an isotropic media. This is predicated upon the
basis that, as the lens expands when the deionized water
is replaced with the saline packing solution, the
30 expansion of the lens in the radial direction, i.e. the



30

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1 increase in the width of the annular band, is the same
as the increase of the diameter of the entire lens.

The relationship between the width of the
peripheral zone of a lens in the final packing solution
and the width of that zone in deionized water steady
5 state conditions, may be expressed as follows:

$$PZ_{\epsilon} = PZ_w(1 + \xi) \quad (9)$$

where: PZ_{ϵ} is the peripheral zone width in the
final packing solution,

10 PZ_w is the peripheral zone width in the
deionized water steady state, and

ξ is a linear expansion factor.

ξ can also be expressed in terms of the final
diameter, D_{ϵ} , of an expanded lens in packing solution
and the diameter, D_w , of the lens in its steady state
15 during inspection while in deionized water, as follows:

$$\xi = \frac{D_{\epsilon} - D_w}{D_w} \quad (10)$$

For example, a lens may have a final design
20 diameter, D_{ϵ} , of 14.200 mm, and a steady state diameter
in deionized water, D_w , of 895 pixels, or 12.670 mm.
Using equation (10), the linear expansion factor, ξ , for
this lens equals 0.12076. Substituting this value for ξ
in equation (9), yields equation (11).

25

$$PZ_{\epsilon} = PZ_w(1.12076) \quad (11)$$

30 With one type of lens that system 10 has been
used to inspect, the lens has an outside diameter of
14.200 mm, and the back optical zone of the lens has a

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1 diameter of 13.000 mm. The total linear distance
consumed by the peripheral curve is the difference of
these two values, or 1.200 mm, and the width of the
peripheral zone, PZ_{ϵ} of the lens equals half that value,
5 or 600 microns. Rearranging equation (11) to determine
 PZ_w , and then substituting 600 microns for PZ_{ϵ} in the
equation, yields:

$$PZ_w = \frac{PZ_{\epsilon}}{1.12076} = \frac{600 \mu\text{m}}{1.12076} = 535 \mu\text{m} \quad (12)$$

10 Thus, using a first approximation to the width of
the peripheral zone, the width of PZ_w is estimated to be
535 microns. In actual practice, however, the width of
 PZ_w is 580 microns. Thus, the model underestimates the
15 actual width of the peripheral zone by about 8 percent.
This could be due, for example, to nonlinear expansion
of the lens in the final packing solution, or to the
fact that the molds, in which the ophthalmic lenses are
made, have a different target dimension for the optical
zone diameter.

20 The preferred embodiment of the algorithm used in
system 10 rejects any lens that has a peripheral zone
width less than 332 μm . The parameter $C_{\text{minPZdist}}$ has
the value of 332, and is the minimum peripheral zone
width.

25 In order to determine decentration of a lens, a
comparison is made between the outer edge of the lens
and the Peripheral Zone/Center Zone edge. It is
expected that both edges are circular and that localized
30 deviations in the edges are not relevant to a final
decentration determination. The circular model

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1 determined during the Lens Find operation is used to
2 characterize the outer edge of the lens. Then, three
3 data points are extracted on that model of the lens
4 outer edge at approximately 0, 180, and 270 degrees.
5 These data points are used as references for the
6 location of three windows. The windows are located
7 interior to the model of the lens outer edge and are
8 used to find the Peripheral Zone/Center Zone boundary.
9 Figure 23 shows the location of these three windows.

10 Within each of the windows, a large one
11 dimensional edge operator is performed, and Figures 24
12 and 25 show the gradient masks used to enhance vertical
13 and horizontal edges respectively. Specifically, the
14 windows at 0 and 180 degrees use the vertical edge mask
15 described in Figure 24, and the window at 270 degrees
16 uses the horizontal edge mask described in Figure 25.

17 Next, a measure of edge strength along the length
18 of the windows is made. For the windows at 0 and 180
19 degrees, each column has an edge strength associated
20 with it. A summation of gradient values for the column
21 being processed and the columns on either side of that
22 column is compiled for each column in the window. A
23 pass is then made over all these edge values to
24 determine which column contains the greatest edge
25 strength. Figure 26 shows a representation of a
26 processed window and the resulting edge strength
27 histogram.

28 For the windows at 0 and 180 degrees, this peak
29 column found from the histogram is considered to define
30 the Peripheral Zone/Center Zone boundary. The row
31 centers of the windows are the corresponding row



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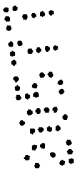
coordinates that defines the two data points on the
1 Peripheral Zone/Center Zone boundary. Equations (11)
and (12) show the histogram compilation and analysis in
equation form.

5 column edge strength [j] =
$$\begin{aligned} & \sum (\text{gradient magnitudes})_{j-1} + \\ & \sum (\text{gradient magnitudes})_j + \\ & \sum (\text{gradient magnitudes})_{j+1} \end{aligned} \quad (11)$$

where;
j = the column being processed

10 gradient magnitude= the gray-level result of the edge
enhancement operator
boundary column= maximum value of column edge
strength [j] array for all values
of j (12)

15 From a conceptual standpoint, the processing in
the window at 270 degrees is identical to the processing
in the other two windows. However, for the window at
270 degrees, the edge of interest is horizontal instead
20 of vertical, and hence all operations are essentially
rotated by 90 degrees. The window dimensions are
rotated, the horizontal edge mask is used, a row by row
edge strength histogram is compiled and the row value of
the Peripheral Zone/Center Zone boundary is the final
25 result. The column center of the window is the
corresponding column coordinate that defines a data
point on the Peripheral Zone/Center Zone boundary.
Equations (13) and (14) show this analysis in equation
form.



30



35



1 row edge strength [i] = $\frac{\sum (\text{gradient magnitudes})_{i-1} + \sum (\text{gradient magnitudes})_i + \sum (\text{gradient magnitudes})_{i+1}}{\sum (\text{gradient magnitudes})_{i+1}}$ (13)

where; i = the row being processed

5 gradient magnitude = the gray-level result of the edge enhancement operator

boundary row = maximum value of (row edge strength [i]) for all values of i (14)

10 With these three Peripheral Zone/Center Zone boundary data points, a circular model is calculated.

The angle of the axis upon which the minimum and maximum decentration occurs is calculated from the displacement of the lens' outer edge model center and the Peripheral Zone/Center Zone model center. This relationship is described in equation (15).

decentration axis angle = $\arctan \left(\frac{((\text{row center})_{\text{lens}} - (\text{row center})_{\text{PZCZ}})}{((\text{column center})_{\text{PZCZ}} - (\text{column center})_{\text{lens}})} \right)$ 15)

20 Once this angle is determined, the rows and columns of points on the Peripheral Zone/Center Zone model and on the lens outer edge model are calculated at that angle. Distances from these two points to the lens' outer edge model are then calculated. The difference in these two distances becomes the minimum decentration value. If the value turns out to be smaller than the minimally accepted distance specified by the parameter "C_minPZdist," the lens is failed due to decentration. Figure 27 shows the geometric relationship of the decentration calculation.

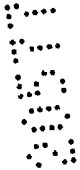


35

Tic Marks

1 If the lens has passed the decentration test,
then the area of the package used for frictional
adhesion during water removal, known as the tic marks
zone, or TMZ, is processed. The purpose of the TMZ
5 processing is to blend the generally lower intensity of
the TMZ into the average intensity profile surrounding
the center zone, or CZ. Once the TMZ has been blended
into the CZ, the entire CZ can be processed for
irregularities. The technique used for blending the TMZ
10 into the CZ is preferably conducted in such a way as to
retain object information within the TMZ.
Alternatively, the TMZ could be evaluated separately
from the rest of the CZ for irregularities indicative of
the presence of a flaw in the TMZ. However, it is
15 preferred to blend the TMZ into the CZ, and then to
inspect the entire CZ at one common flaw intensity
threshold.

The package center and the lens center do not
have to be the same within the image field of view.
20 However, even when these centers do not coincide, the
package tic marks appear in regular patterns within the
image. Typically the locations of these tic marks vary
only a few pixels from image to image, and Figure 28
shows, for example, the approximate location of the tic
25 mark pattern within an image. Because the locations of
these tic marks are so consistent, the preferred search
routine to find the TMZ limits the field of search to a
relatively small area within the image. In particular,
the total image may contain 1,048,576 pixels, while the



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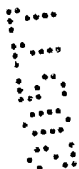


1 typical search area for the first tic mark may have
about 3,000 pixels.

5 With a preferred embodiment, a first of the TMZs
is found by searching in a comparatively large region in
which that TMZ is expected to be located. For example,
Figure 29 illustrates a search region that may be
searched for a first tic mark. Once one TMZ is found,
the position of that TMZ is used to help find the other
TMZs. In particular, smaller but more precisely located
search regions may be identified relative to the
10 location of the first TMZ to look for the other TMZs.
For example, the search regions for the second, third,
and fourth tic marks may be only 400 pixels in area.
Figure 30 shows one example of search regions that may
be used to locate the TMZ areas.

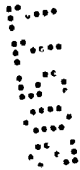
15 More specifically, preferably tic mark handling
begins by searching a relatively large rectangular
region to locate the left-horizontal tic mark. Row and
column reference points that define the location of the
search region are specified by the parameters
20 "C_r_tickofst" and "C_c_tickofst," respectively. A
large number of equally spaced column search vectors are
traversed across the search region. Search vectors are
traversed from top to bottom until a one-dimensional
gradient magnitude indicates the presence of the tic
25 mark boundary. Gradient calculation is defined by
Equation (16).

$$\text{tick mark search gradient} = \text{abs} (P_{1-2,j} - P_{1,j}) \quad (16)$$



1 Gradient magnitude is compared to a threshold
value found in a parameter "C_tickhthr." If, while
searching along a particular search vector, a calculated
gradient is greater than or equal to the threshold, the
top boundary of a tick mark, along that search vector,
5 is found. If a top boundary is found, a search is then
conducted along the same column, from bottom to top, in
order to locate the bottom boundary of the tic mark.
This search vector cycle may be conducted for all search
vectors within the search region; and for example,
10 Figure 31 shows a search region search vectors that may
be used to locate the left-horizontal tic mark.

Boundary information about a tic mark, obtained
from all the search vectors in the region of a tic mark
15 is then analyzed to obtain the row centroid of the tic
mark. Search vectors that have detected object
boundaries that are too wide or too thin to be a tic
mark, are preferably discarded. Preferably, those
search vectors that did not find any object are also
discarded. Next, the remaining vectors are checked to
20 determine the longest segment of consecutive search
vectors that identified a potential tic mark object, and
the longest object identified is considered to be the
tic mark. This procedure is designed to distinguish tic
marks from smaller objects or items, referred to as
25 noise, and from lens defects that may be encountered
within the search region. The row centroid is then
calculated from the search vector boundaries of the
longest identified segment, and Figure 31 also
30 illustrates this search vector process and the



30

35

1 relationship of the search vectors to row centroid
determination.

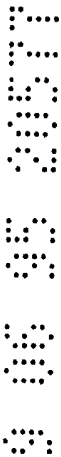
5 The next step is to identify the column
boundaries of the tic mark. To do this, two search
vectors are searched, or traversed, along the already
determined row centroid of the tic mark. These two
vectors are searched outward from the column average of
the longest identified segment. One of these vectors is
searched to the left to find the left boundary of the
tic mark, and the other vector is searched to the right
10 to find the right boundary of the tic mark. A grey-
level threshold is preferably used to identify column
boundaries of the tic marks since flaws found in tic
marks could cause gradient information to be misleading.
15 In addition, flaws in a tic mark appear darker than the
rest of the tic mark. For this reason, a search using a
grey-level threshold procedure does not erroneously
identify flaws inside the tic marks as boundaries of the
tic mark, and a grey-level threshold is able to
20 distinguish a tic mark from the lighter surrounding
region.



25 Preferably, the grey-level threshold used to
identify row boundaries of a tick mark is calculated as
a fixed percentage of the average grey-level of two
regions that surround the tic mark. As an example,
Figure 32 shows two neighboring regions of a tic mark
that may be used to calculate a grey-level threshold.
When a pixel is encountered along the row search vector
that is greater than or equal to this threshold, a
boundary has been identified. The column centroid of
30

1 the tic mark is then calculated from these two
boundaries.

5 Alternatively, a gradient calculation could be
used to identify the left and right boundaries of a tic
mark. To do this, for example, a search vector may be
traversed from the right side of the bounding region
leftward to find the right edge of the tic mark.
Gradient magnitudes may be calculated according to
Equation (1); and when a gradient is greater than or
equal to the threshold specified by the parameter
10 "C_tickwthr," the tic marks right boundary is found. A
search vector may then be similarly traversed from the
left side of the bounding region rightward to find the
tic marks left boundary. Figure 33 shows conceptually
how a tic mark is handled on a row-by-row basis.



15 Once the location of a TMZ is determined, it is
blended with the surrounding image information using a
procedure referred to as an offset transformation. The
transformation essentially raises the grey-level of the
tic mark, on a row-by-row basis, to a level that allows
20 it to blend in with its neighboring region. With this
procedure, defect information is retained, and an
analysis of the transformed region for defects is later
performed by the same algorithm used for all other areas
of the center zone of the lens.

25 More specifically, in this procedure, the grey-
levels for two areas near the TMZ are averaged. These
two regions may be the same as those used during the tic
mark's centroid determination, shown for example in
Figure 32. A difference, Δ_{row} , is calculated between
30 the average grey-level outside the TMZ and each of the

1 tic mark rows; and for each row inside the TMZ, the
value of Δ_{row} is added to the value of each pixel along
that row. The result of this offset transformation for
a TMZ row containing a defect is depicted in Figure 34.
5 As this Figure illustrates, the image of the pinhole
flaw in the lens has been retained, but the TMZ itself
has been blended into the neighboring region of the
image surrounding the TMZ. Because of this attribute of
the transformation process, the TMZ may now be examined
10 uniformly as part of the CZ by the CZ inspection
algorithm.

Alternatively, a TMZ may be processed, not only
by means of the linear offset transformation, but also
to increase the gain of the pixels within the TMZ prior
to such a transformation. This may improve the ability
15 of the inspection algorithm to detect defects within
the TMZ. Multiplying the TMZ by some gain factor prior
to determining the offset value Δ_{row} would increase the
gradient of a defect object within the TMZ. However,
20 this may also have the adverse effect of making the TMZ
noisier.

Once row and column centroids are found, a
transformation is performed on the "tic mark." The
transformation is restricted to a small rectangular
region that encompasses the "tic mark" and is centered
25 about the "tic mark's" centroid. The height (short
dimension) and width (long dimension) of the bounding
region is specified by the parameter "C_tickhgt" and
"C_tickwid," respectively.

30 The other three tic marks may be found and
processed in the same manner. Preferably, the search

1 regions for these other three tic marks are each
2 somewhat smaller than the search region for the first
3 tic mark, since starting locations for these other three
4 tic marks are referenced from the left-horizontal tic
5 mark centroid. Also, for vertical tic marks, the
6 operations are rotated by 90 degrees because the long
7 dimension of the tic mark is in the row direction
8 instead of the column direction. Figure 30 shows, for
9 example, the search regions that may be used to find the
10 other three tic marks.

11 As with the left-horizontal tic mark, the
12 transformation of the tic mark grey values does not
13 detect flaws. The tic marks are preprocessed to a point
14 where they can be properly handled by the algorithm used
15 in the lens Center Zone analysis. In this way, the tic
16 marks themselves will not be considered flaws, but true
17 flaws that overlap or lie within a tic mark will be
18 detected.

Holes and Marks in Center Zone

19 Holes and marks in contact lenses typically
20 appear as dark spots within the center zones of the
21 images of the contact lenses. Such features may be
22 discerned from the white background using gradient
23 search algorithms. However, a gradient search to define
24 objects in the CZ would take a comparatively large
25 amount of time to perform. Because the entire image
26 consists of 1,048,576 pixels, approximately 20 million
27 operations would be required to test the entire image.

28 The center zone of a lens is considered to be all
29 portions of the lens interior to the peripheral zone,
30 and Figure 35 shows the location of this region. Actual



1 boundaries for this region are preferably defined from
the model of the Peripheral Zone/Center Zone edge that
was derived during decentration calculation.

5 A modified version of blobs analysis is used as a
means of detecting flaws. Like the analysis of the
peripheral zone, discussed below, blobs analysis of the
central zone uses eight connectivity analysis to segment
objects. However, two important differences exist in
10 the implementation of blobs analysis in the peripheral
and center zones. In the central zone, the pixel
characteristic used to distinguish foreground objects
from background is strictly gradient magnitude. This
magnitude is defined by Equation (17).

15
$$\text{gradient} = \text{abs}(P_{i,j-1} - P_{i,j+1}) + \text{abs}(P_{i-1,j} - P_{i+1,j}) \quad (17)$$

If the gradient magnitude of a pixel is greater
than or equal to the threshold specified by the
parameter "C_czbinthr," the object is considered to be
20 foreground.

25 The second difference is that, in the central
zone, blobs analysis is implemented such that the region
processed uses a pseudo subsampled technique. Pixels in
every other row and every other column are used in the
blob's connectivity analysis. The gradient calculation,
however, uses the actual neighbors of the pixel being
30 processed, as described above in Equation (17). Figure
36 shows the neighborhoods used for subsampling and
gradient calculations.

Once a full pass has been made over the image,
35 the sizes of those objects found are calculated. Those

1 objects that exceed the object size specified by the
parameter "C_czminblob" are considered severe enough to
fail the lens. If one or more of these objects has been
found, the lens is failed and further processing is
aborted.

5 By using a subsampling technique, the same area
can be processed with fewer operations. Figure 36 shows
the basic scheme of the pixel subsampling pattern chosen
to reduce the number of needed calculations to under
1,310,720. Visually, this search scheme appears like a
10 modified checkered design. Every other row and every
other column are skipped during analysis of the point of
interest.

15 At each subsampled pixel, the surrounding pixels
are analyzed by a bi-directional gradient operation of
equation (18) to determine if there are large gradients
near the pixel of interest.

$$G=(abx(P_{j-1} - P_{j+1}) + aby(P_{i-1} - P_{i+1})) \quad (18)$$

20 If there is a gradient larger than parameter
C_czbinthr, then that pixel is placed in a specified
section of processor memory, referred to as foreground.
As soon as this occurs, the pixel is tested using blob
analysis to determine the object in the foreground space
25 to which the pixel belongs, i.e., this analysis
determines if there are any objects nearby to which the
pixel of interest belongs. If the pixel of interest
does not belong to any existing objects, a new object is
30 identified. However, if the pixel of interest belongs
to an existing object, the object is tested against a



1 size threshold. If adding the newest pixel of interest
to the object places the object over the total
foreground pixel size threshold, C_czminblob, then the
object is considered too large and the lens is failed.

5 Thus, it may not be necessary to evaluate the
entire image within the boundary of the CZ. If an
object is found that exceeds the threshold for maximum
size, C_czminblob, further processing is aborted.

10 Any object encountered in the subsampled search
of the CZ is detected as a defect if it is large enough.
For instance, the threshold C_czminblob may be 25 pixels
in area. Since that is in units of subsampled pixels,
it is actually representative of a 9x9, or 81 pixels in
area using object space. In one embodiment of system
15 10, nine pixels are 127 microns in length, and thus 5
pixels cover 71 microns. Therefore, with this
procedure, the longest possible acceptable CZ defect
will cover $9 \times 2 = 18$ pixels of area and have a maximum
dimension of 127 microns. However, due to both pixel
20 overlap and the fact that the gradient calculation
effectively adds to the width of an object, smaller
defects are easily detected by the preferred inspection
algorithms.



25 For example, perfectly round objects appear to be
larger foreground objects than actual objects. In
practice, an 0.080 millimeter diameter flaw on a
calibration standard defect is detected by the algorithm
substantially 100% of the time. Because the 80 micron
dot extends across an actual 6 pixels, it is found by
the gradient calculations of the subsampled pixels and
30 establishes itself as a foreground object spanning 9

1 actual pixels, 5 pixels in foreground space. This
causes the algorithm to reject the lens on the basis
that the flaw exceeds the C_czminblob parameter. This
means that the minimum rejectable center defect is set
at 80 microns, for a C_czminblob parameter equal to 25
5 pixels of area in foreground space. If C_czminblob was
set at 16, then this size would shrink to a minimum
rejectable center defect of 45 microns. However, it has
been found that excellent results may be obtained when
C_czminblob is set at 25.

10 Puddles

Puddles, which are cosmetic flaws, are slight
depressions in the surface of the lens, and Figure 37
shows a cross section of a typical puddle. The
depression only involves one of the lens surfaces,
15 unlike another defect known as a hole, which penetrates
the entire lens. Since the depression is very gradual,
puddles are, in general, difficult to see in a white
light illumination system. Phase contrast systems, such
as a modified Schlieren system, tend to enhance the
20 edges of the puddles better. In a white light system,
such as employed in system 10, only the deepest and most
severe puddles are normally visible. In a phase
contrast system, even index of refraction deviations
caused by the heat from a finger are discernable. The
25 result of the phase contrast hyper-sensitivity is that
it tends to enhance less serious cosmetic flaws and
display them in such a way as to reject lenses
unnecessarily. In a phase contrast system of
illumination, very shallow puddles appear just as
30 serious as do the deeper flaws.



1 Puddles tend to occur primarily on the outer
region of the lenses and are the result of subtle
variations in the SSM process. Lens puddles form during
the curing process. Some puddles may disappear or
5 become virtually invisible when a lens is hydrated, in
which case the puddle is said to hydrate away. What
actually occurs is that the hydration process smoothes
the edges of a nearly invisible puddle into an invisible
surface irregularity.

10 The preferred embodiment of the algorithm
inspects for puddles in two areas, the center zone, CZ,
and the peripheral zone, PZ. The approaches to finding
puddles in these two different zones originate from the
actual appearances of puddles in these regions. In the
15 CZ, puddles appear as dark lines on a white background,
while in the PZ, the puddles are partially obscured by
image noise and appear to have white halo accents.

Puddles in the Center Zone

Any puddle severe enough to cast a dark line in the CZ
is rejectable in the same manner as any other mark.
20 Preferably, the algorithm does not distinguish between
individual defects. It is not important which CZ defect
causes the image processor to fail the lens. A pristine
lens will pass, and a lens with a puddle, or any other
type of flaw in the CZ, will fail and consequently be
25 rejected by the inspection system.

Puddles that enter into the CZ are usually very
large. Moreover, such puddles usually cross the PZ/CZ
junction. Puddles that cross this junction are harder
to detect in the region of the PZ than in the CZ. Less
30

1 severe puddles, which have shallower depths and fainter
lines, are more visible in the CZ than in the PZ.

Puddles in the Peripheral Zone

5 The peripheral zone is considered to be an
annulus shaped region bounded by the outer edge of the
lens and the boundary between the peripheral and center
zones of the lens, and Figure 38 shows this region of a
lens. Puddles in the PZ do not fall within the normal
definition of center of lens flaws. Nevertheless,
10 preferably, the inspection algorithm is able to find
puddles in the PZ.

15 The peripheral zone has some special features
associated with it that warrant it being processed
separately from the center zone. The grey-level of the
peripheral zone is significantly lower than the center
zone which causes noticeable gradients when passing from
one zone to the other. These resulting gradient
magnitudes could easily be mistaken for flaws, or could
reduce detection sensitivity, if a thresholding test was
20 used as a means of compensation. The lower grey-level
in the peripheral zone is also accompanied by a texture,
both of which cause flaws to be less pronounced. Also,
since the PZ boundary is irregularly shaped, or rough,
and contains gradient magnitudes within its annular
region, many of these noisy image features resemble
25 flaws. Finally, the peripheral zone is a region in
which puddles are typically located. As mentioned
above, puddles are characterized by subtle edges that
tend to be parallel or perpendicular to the curvature of
the lens outer edge.

30

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1 A modified version of blobs analysis is used as a
means of segmenting foreground objects from background
objects. If the foreground objects meet certain size
and intensity criteria, they are considered to be flaws.
5 Intensity criteria, which is used to distinguish
individual pixels as foreground from background, is
specified by the parameter "C_pztantr." Size criteria
is specified by the parameter "C_pzminblob."

Blobs analysis makes a single raster scan pass
10 over the image, determines connectivity of each new
pixel with existing objects, and assigns unique labels
to all newly encountered objects. A linked list keeps
track of all objects found in the image and is updated
in the event that objects which were initially
15 determined to be separate become connected later in the
image. Connectivity is preferably implemented such that
if a pixel-of-interest is considered a foreground pixel
and any of its eight immediate neighbors belongs to a
particular object, then that pixel-of-interest is
20 assigned to that particular object. In other words, the
blob's segmentation analysis is based on eight
connectivity analysis.

Each pixel in the PZ annular region is considered
for inclusion into the image foreground in a heavily
modified blob analysis. All foreground pixels are
25 classified as part of objects that, if they exceed size
limitations, cause rejection of the lens.

Traditional blob analysis requires a binary
image, where each pixel has the value of zero or one,
i.e., foreground or background. In the preferred
30 algorithm used in system 10, the characteristic

1 distinguishing a pixel from foreground to background is
the scalar dot product of the pixel gradient magnitude
vector and the tangent direction vector. If the dot
product result is larger than $C_{pztantr}$, the pixel is
5 considered part of the foreground.

5 Blobs analysis is typically implemented on binary
images where segmentation is based on pixel values of 0s
and 1s. Implementation of blobs analysis in the
peripheral zone is unique in that the pixel
10 characteristic used to distinguish foreground objects
from background is the vector dot product of the pixel's
gradient magnitude vector and a tangent direction
vector. The gradient magnitude vector of a pixel
consists of its horizontal and vertical gradient
15 components. The tangent direction vector of a pixel
consists of weights based on the horizontal and vertical
components of a vector that is tangent to the outer edge
of the lens. The point on the outer edge at which the
tangent is taken is defined by a line that intersects
20 the pixel-of-interest and the center of the lens.

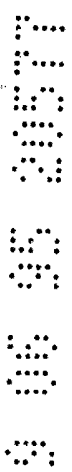
20 Figure 39 shows the relationship of both vectors.

In general, if the direction of the gradient
vector $G(f(x,y))$ is parallel to the tangent vector on
the lens edge, then the resulting dot product will be
large. This circumstance occurs when a puddle edge
25 inside the PZ extends parallel to the lens edge.

The dot product between the gradient vector and
the tangent vector on the lens edge, is defined in
equation (19).

30

35



1
$$Dotproduct = T \cdot G = \begin{bmatrix} T_x \\ T_y \end{bmatrix} \cdot \begin{bmatrix} G_x \\ G_y \end{bmatrix} \quad (19)$$

5 Tangent direction vector and gradient magnitude vector components are calculated in a manner referred to as on the fly for every pixel found in the peripheral zone region. The tangent direction vector and its components are described in Equations (20) and (21).

10
$$horizontal_{tan} = (row_{POI} - row_{lens}) * Scale\ Factor) / radius_{POI}$$

where the subscripts; (20)

tan = a component associated with the tangent direction vector

POI = a coordinate position of the "pixel-of-interest"

15 lens = a coordinate position of the lens' center

and,

Scale Factor is specified by the parameter "C_pzscale".

20
$$vertical_{tan} = (column_{lens} - column_{POI}) * Scale\ Factor) / radius_{POI} \quad (21)$$

where the subscripts;

tan = a component associated with the tangent direction vector

25 POI = a coordinate position of the "pixel-of-interest"

lens = a coordinate position of the lens' center

and,

30 Scale Factor is specified by the parameter "C_pzscale".

35

1 As Equations (20) and (21) stand, enhancement is
provided for those gradients that are parallel to the
tangent vector. Enhancement is greatest for those edges
exactly parallel to the tangent vector and decreases to
5 a minimum as the gradient becomes perpendicular to the
tangent vector.

Since it is actually desirable to enhance those
gradients that are close to perpendicular as well as
parallel to the tangent vector, a check is made to
10 determine which case the gradient is closest to and an
adjustment is potentially made to Equation (20) and (21)
results. To determine whether the gradient is closer to
parallel or perpendicular, a comparison between the
tangent direction vector's dominant component and the
15 gradient magnitude vector's dominant component is made.
If the dominate gradient magnitude vector component is
different than the dominate tangent direction vector
component, then the gradient is closer to perpendicular
than parallel. For example, if the gradient magnitude
20 vector's vertical component is greater than its
horizontal component and the tangent direction vector's
horizontal component is greater than its vertical
component; the gradient is closer to perpendicular than
parallel. Equation (22) shows the adjustment made if
this is the case.

25 If the gradient is closer to being perpendicular
than parallel to the tangent vector,

```
swap tangent vector components
temporary result = horizontaltan
30 horizontaltan = verticaltan
```

35

1 vertical_{tmn} = temporary results (22)

Equations (23) and (24) give maximum weight to those gradients that are exactly parallel or perpendicular to the tangent vector. Weights trail off to a minimum at ± 45 degrees from parallel or perpendicular. The resulting tangent direction vector is shown in Equation (23).

10 tangent direction vector =
$$\begin{bmatrix} \text{horizontal}_{tm} \\ \text{vertical}_{tm} \end{bmatrix}$$
 (23)



15 A pixel's gradient magnitude vector and components are detailed in Equations (24) through (26).

20 horizontal_{gm} =
$$\frac{\text{abs}(P_{i-1,j+1} + 2 * P_{i,j} + P_{i+1,j-1} - (P_{i+1,j+1} + 2 * P_{i,j} + P_{i-1,j-1}))}{2}$$
 (24)

where;

horizontal_{gm} = horizontal component of the gradient magnitude vector.

25 vertical_{gm} =
$$\frac{\text{abs}(P_{i-1,j+1} + 2 * P_{i,j+1} + P_{i+1,j+1} - (P_{i-1,j-1} + 2 * P_{i,j-1} + P_{i+1,j-1}))}{2}$$
 (25)

where;

vertical_{gm} = vertical component of the gradient magnitude vector.

30

35

1

$$\text{gradient magnitude vector} = \begin{bmatrix} \text{horizontal}_{gm} \\ \text{vertical}_{gm} \end{bmatrix} \quad (26)$$

5 The resulting vector dot product is shown in Equation (27).

vector dot product = gradient magnitude vector • tangent direction vector

10

$$= \begin{bmatrix} \text{horizontal}_{gm} \\ \text{vertical}_{gm} \end{bmatrix} \cdot \begin{bmatrix} \text{horizontal}_{tan} \\ \text{vertical}_{tan} \end{bmatrix} \quad (27)$$

15

$$= (\text{horizontal}_{gm} * \text{horizontal}_{tan}) + (\text{vertical}_{gm} * \text{vertical}_{tan})$$

20 While it is apparent that the invention herein disclosed is well calculated to fulfill the objects previously stated, it will be appreciated that numerous modifications and embodiments may be devised by those skilled in the art, and it is intended that the appended claims cover all such modifications and embodiments as fall within the true spirit and scope of the present invention.

25

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THE CLAIMS DEFINING THE INVENTION ARE AS FOLLOWS:

- 1 1. A system for inspecting ophthalmic lenses,
 comprising:
 a transport subsystem for moving the lenses into
 an inspection position;
5 an illumination subsystem to generate a light
 beam and to direct the light beam through the lenses in
 the inspection position;
 an imaging subsystem to generate a set of signals
10 representing selected portions of the light beam
 transmitted through the lenses; and
 an image processing subsystem to receive said
 signals from the imaging subsystem and to process said
 signals according to a predetermined program to identify
15 at least one condition of each of said lenses;
 wherein the illumination subsystem includes
 i) a light source to generate the light beam,
 ii) means to direct the light beam generally in
 a first direction and through lenses in the inspection
20 position,
 iii) a diffuser located in the path of the light
 beam to form the light beam with a generally uniform
 intensity across a transverse cross-section of the light
 beam,
 iv) a lens assembly to focus a portion of the
25 light beam passing through the lenses onto an image
 plane, and to focus a portion of the light beam onto a
 focal point in front of the image plane to form a
 diffuse background pattern on the image plane.
30 2. A system according to Claim 1, wherein the
 lens assembly includes a doublet lens and a field lens

1 located in series between the light source and the
inspection position.

3. A system according to Claim 2, wherein the
doublet lens has a first focal point in the diffuser and
5 a second focal point in front of the image plane.

4. A system according to Claim 3, wherein the
ophthalmic lenses are in packages having an optical
power, and the field lens compensates for the optical
power of the packages.

5. A method for inspecting ophthalmic lenses,
10 comprising:

moving the lenses into an inspection position;
generating a light beam;
generally directing the light beam in a first
15 direction and through the lenses in the lens inspection
position;

focusing a portion of the light beam passing
through the lenses onto an image plane to form images of
the lenses on said plane;

20 focusing a portion of the light beam onto a focal
point in front of the image plane to form a diffuse
background pattern on the image plane;

generating a set of signals representing the lens
images formed on the image plane;

25 processing said signals according to a
predetermined program to identify at least one condition
of each of the lenses.

6. A method according to Claim 5, wherein the
lenses are located in packages having an optical power,
and wherein:
30

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1 the step of focusing a portion of the light beam
onto the image plane includes the step of locating a
field lens below the inspection position to compensate
for the optical power of said packages; and

5 the step of focusing a portion of the light beam
onto a focal point in front of the image plane includes
the step of locating a doublet lens below the field
lens.

7. A method according to Claim 6, wherein the
10 step of directing the light beam in the first direction
includes the step of diffusing the light beam to provide
the light beam with a generally uniform intensity in a
plane transverse to said first direction.

8. A method according to Claim 6, wherein: the
15 diffusing step includes the step of locating a diffuser
in the path of the light beam; and

the step of locating the doublet lens includes
the step of positioning the doublet lens with a first
focal point on the diffuser.

9. A system for inspecting ophthalmic lenses,
20 comprising

a lens holder for holding the lenses in an
inspection position;

an array of pixels;

25 an illumination subsystem to generate a light
beam and to direct the light beam through the lenses in
the inspection position and onto the pixel array and
including

30 i) a light source to generate the light beam,
ii) a diffuser located in a path of the light
beam to diffuse the light beam, and

35

1 iii) a lens assembly located in the path of the
light beam to focus a portion of the light beam passing
through the lenses onto the pixel array, and to focus a
portion of the light beam onto a focal point in front of
5 the pixel array to form a diffuse background pattern on
the pixel array;

 an imaging subsystem to generate a set of signals
representing the light beam incident on the pixel array;
and

10 an image processing subsystem to receive said
signals from the imaging subsystem and to process said
signals according to a predetermined program to identify
at least one condition of each of the lenses.

15 10. A system according to Claim 9, wherein the
ophthalmic lenses have center and peripheral zones and
borders between said zones, and wherein the illumination
subsystem is adapted to produce an image on the pixel
array of the borders between the center and peripheral
zones of the lenses.

20 11. A system according to Claim 10, wherein the
lens assembly includes:

 a field lens located between the light source and
the inspection position; and

 a doublet lens located between the light source
and the field lens.

25 12. A system according to Claim 11, wherein the
doublet lens has a first focal point on the diffuser.

13. A method for inspecting ophthalmic lenses,
comprising:

30 placing the lenses in an inspection position;
generating a light beam;

35

1 directing the light beam through the lenses and
onto an array of pixels to form images of the lenses
thereon;

locating a diffuser in a path of the light beam
to diffuse the light beam;

5 positioning a doublet lens in the path of the
light beam to focus a portion of the light beam onto a
focal point forward of the pixel array;

10 positioning a field lens in the path of the light
beam to focus a portion of the light beam passing
through the lenses onto the pixel array;

generating a set of signals representing the lens
images formed on the pixel array; and

15 processing said signals according to a
predetermined program to identify at least one condition
of each of the lenses.

14. A method according to Claim 13, wherein the
lenses have center and peripheral zones and boundaries
between said zones, and the directing step includes the
step of forming images on the pixel array of the
20 boundaries between the center and peripheral zones of
the lenses.

15. A method according to Claim 14 wherein the
lenses are in packages having an optical power, and the
step of positioning the field lens includes the step of
25 compensating for the optical power of the lens packages.

16. A method according to Claim 15, wherein the
step of positioning the field lens includes the step of
positioning the field lens between the doublet lens and
the inspection position.
30

17. A system for inspecting ophthalmic lenses substantially as hereinbefore described with reference to the accompanying drawings.

5 18. A method for inspecting ophthalmic lenses substantially as hereinbefore described with reference to accompanying drawings.

10 DATED: 30 April 1999

CARTER SMITH & BEADLE
Patent Attorneys for the Applicant:

15 JOHNSON & JOHNSON VISION PRODUCTS, INC



BGC:JH:#18025.RS1

30 April 1999

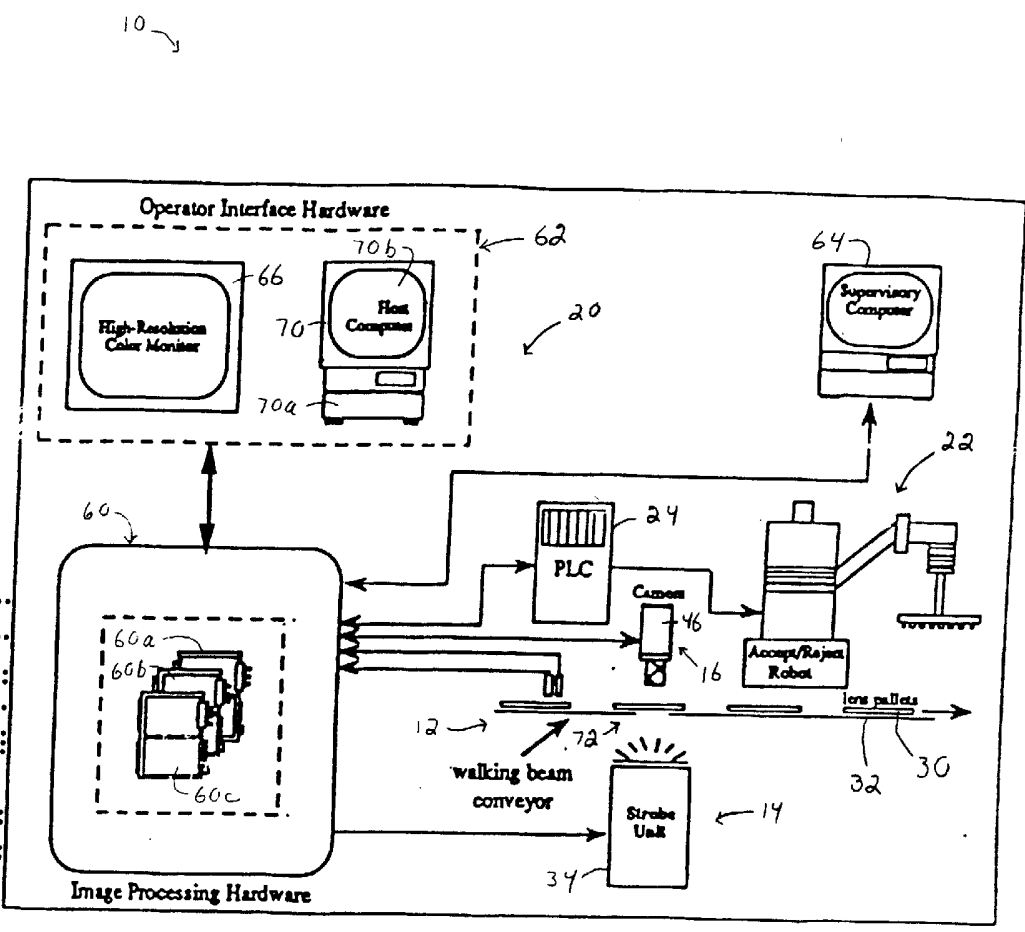


Fig. 1

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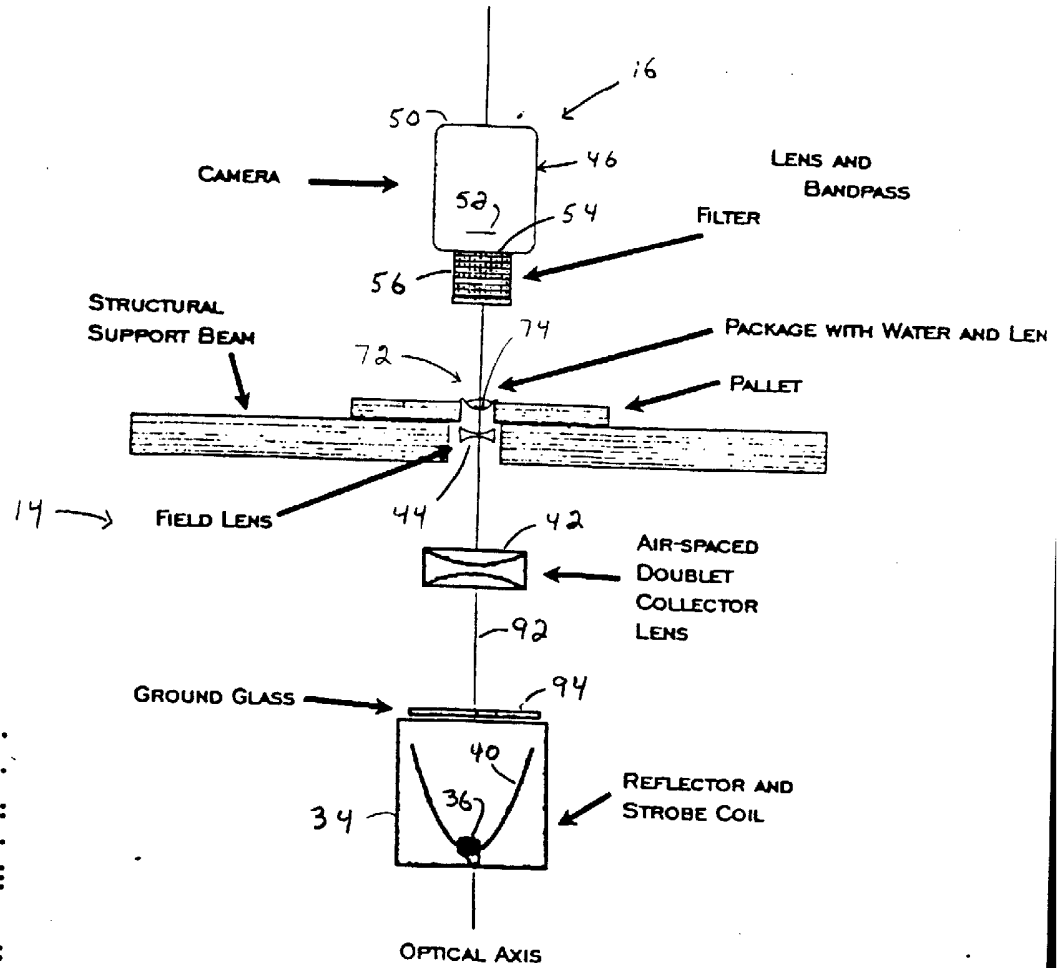


Fig. 2

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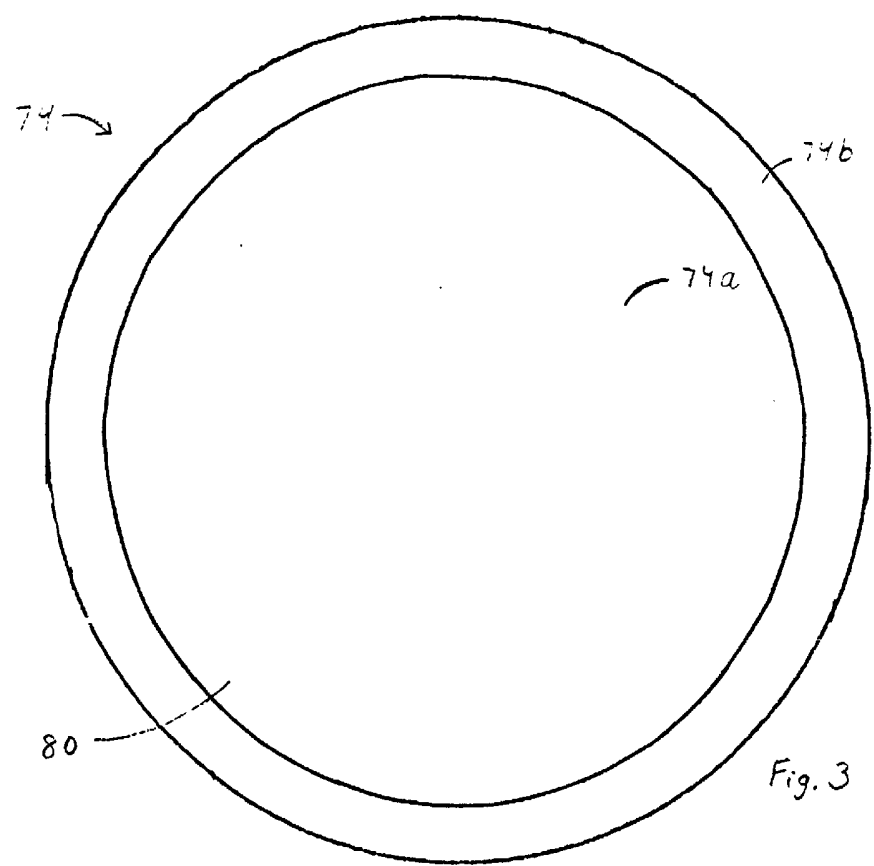


Fig. 3

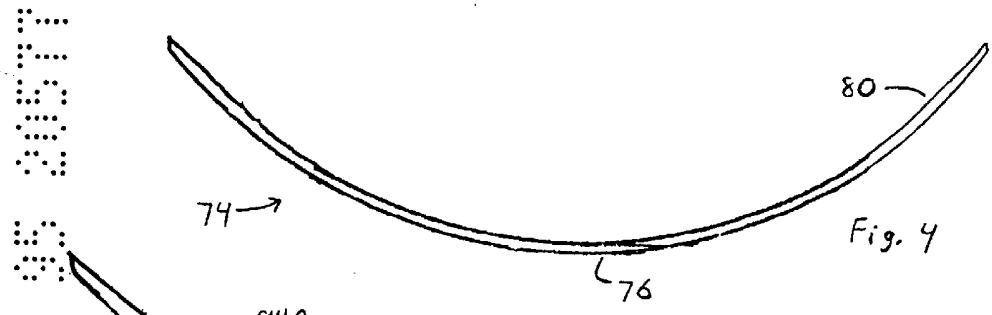


Fig. 4

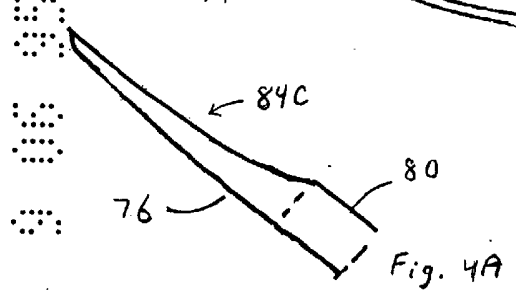


Fig. 4A

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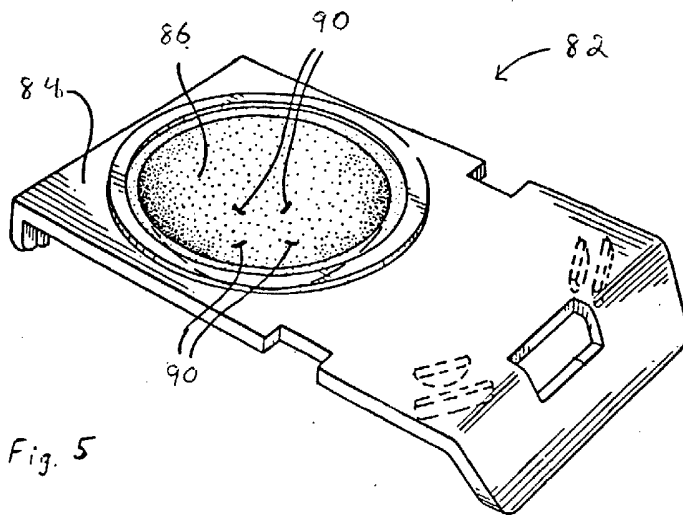


Fig. 5

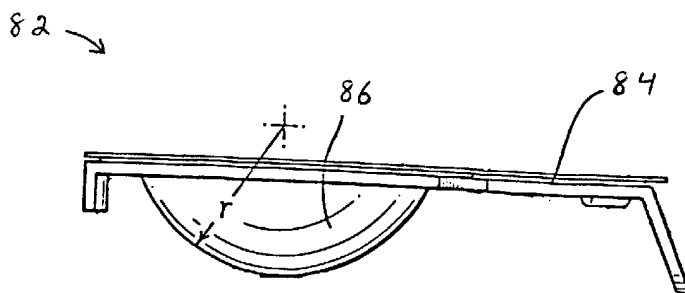


Fig. 6



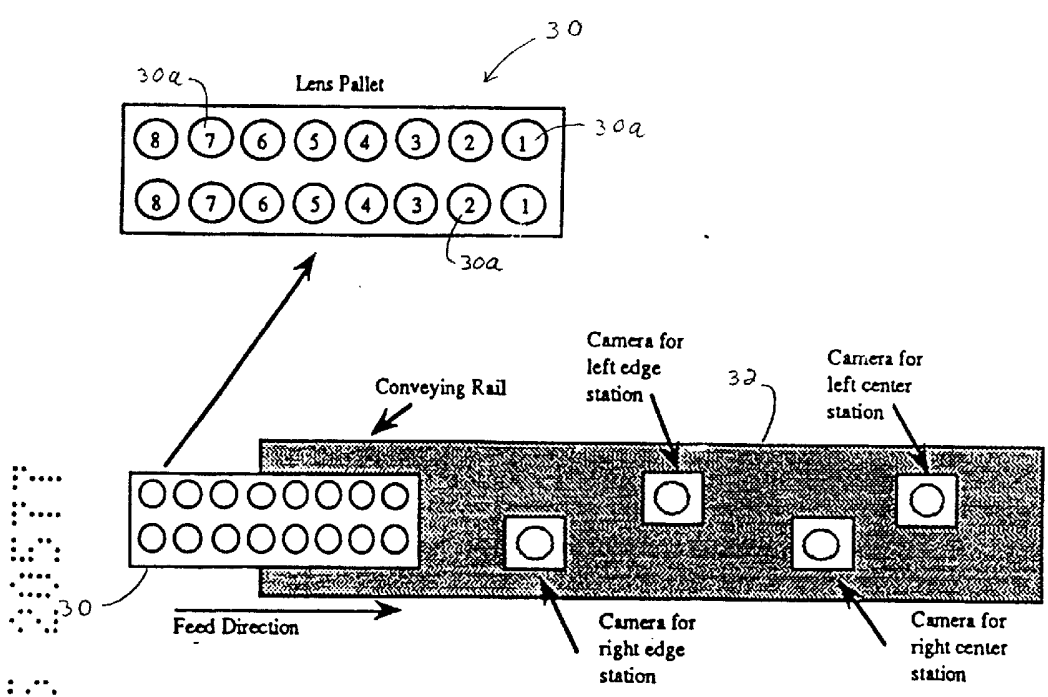


Fig. 7

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$P_{i-1,j-1}$	$P_{i-1,j}$	$P_{i-1,j+1}$
$P_{i,j-1}$	$P_{i,j}$	$P_{i,j+1}$
$P_{i+1,j-1}$	$P_{i+1,j}$	$P_{i+1,j+1}$

Fig. 8

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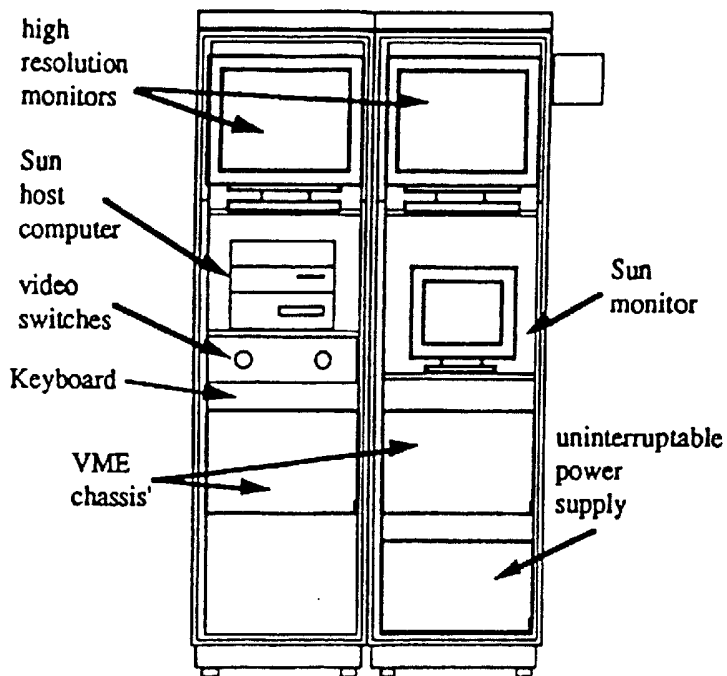


Fig. 9

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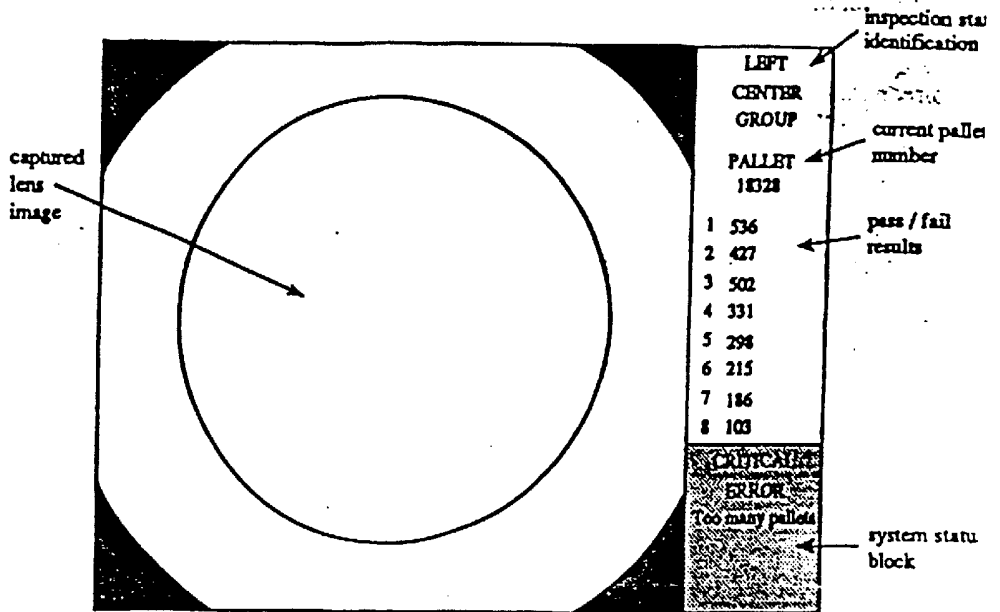


Fig. 10

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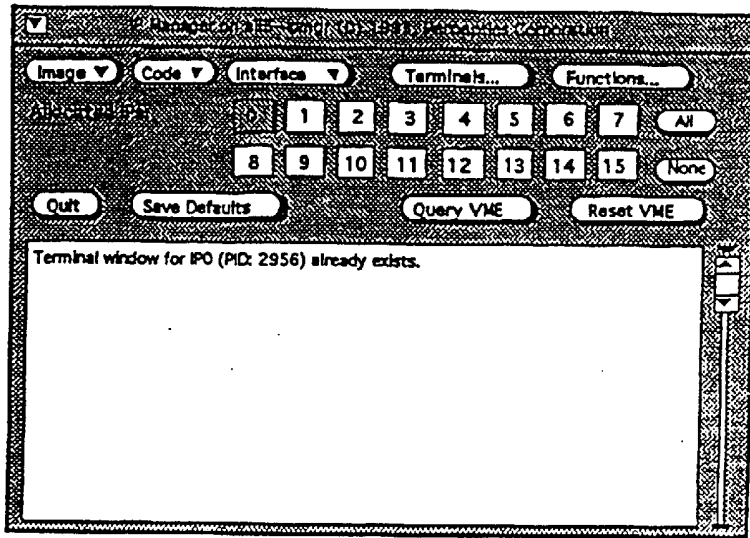


Fig. 11

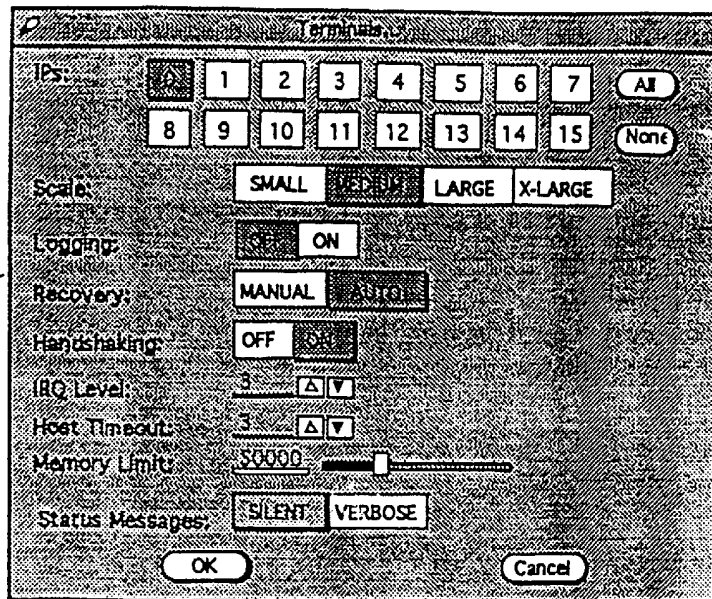


Fig. 12

10/25

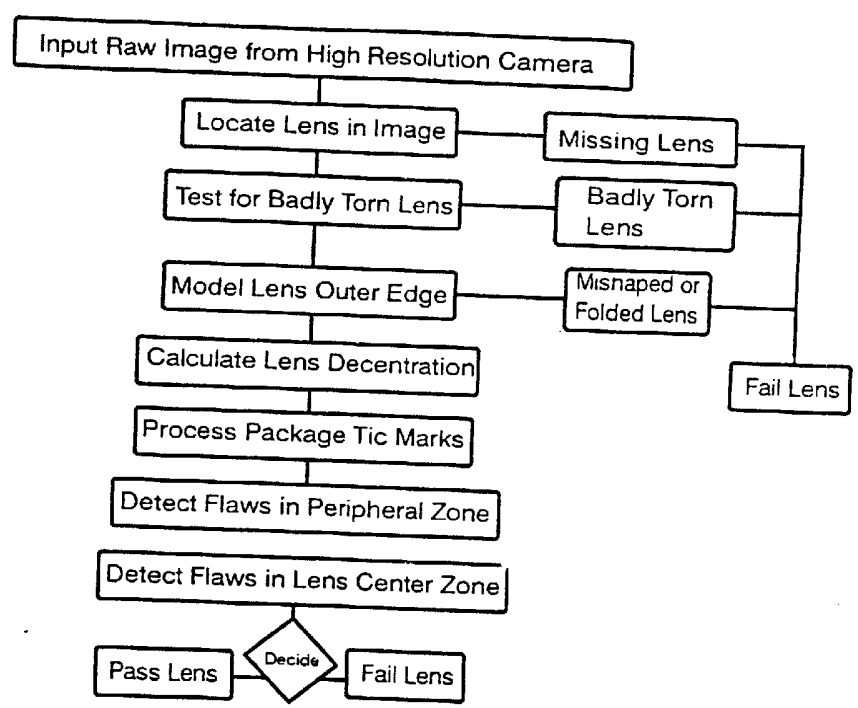
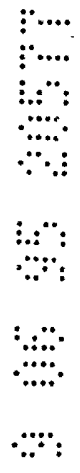


Fig. 13



1/25

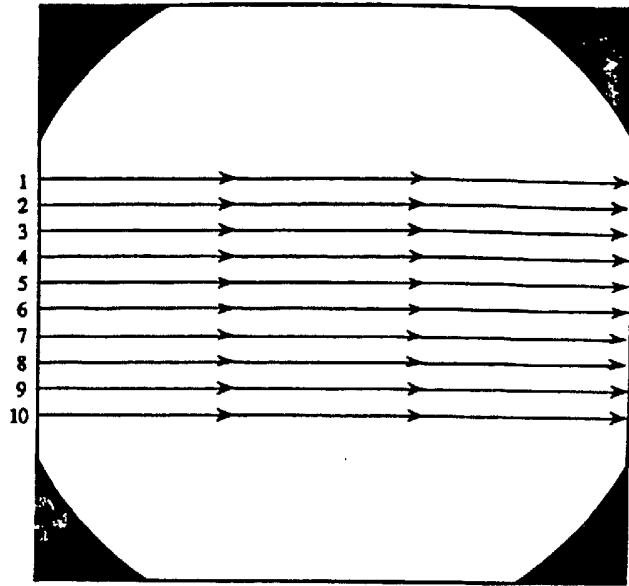


Fig. 14

11 12 13 14 15 16 17 18 19 20

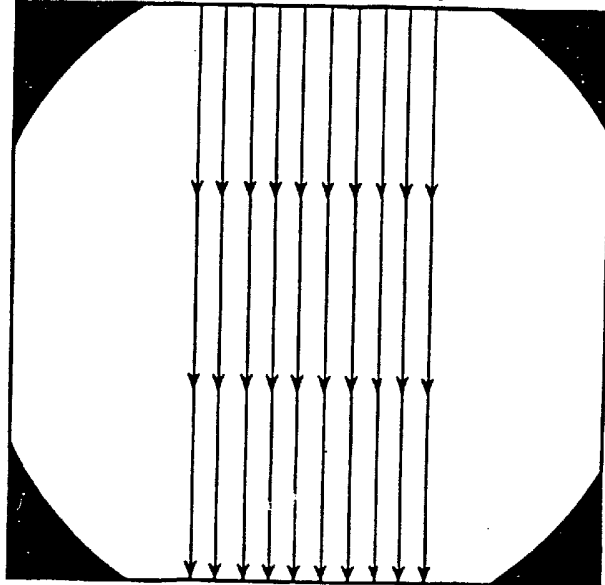


Fig. 15

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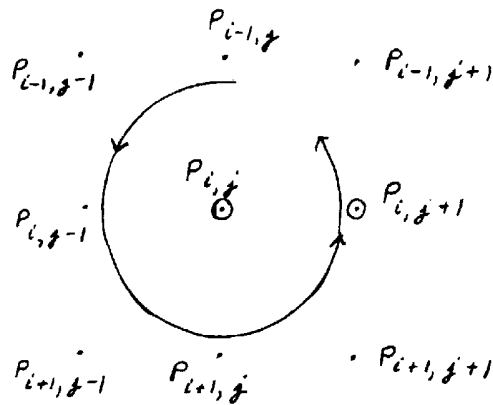


Fig. 16A

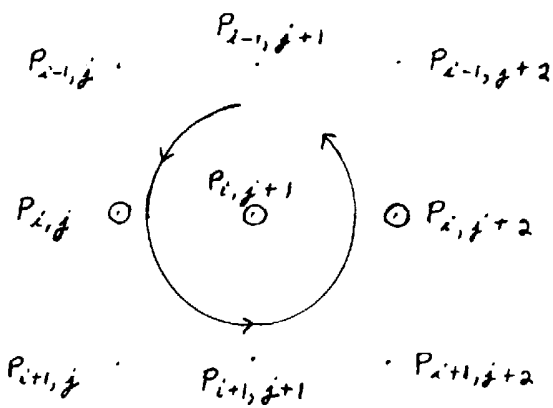


Fig. 16B



13/25

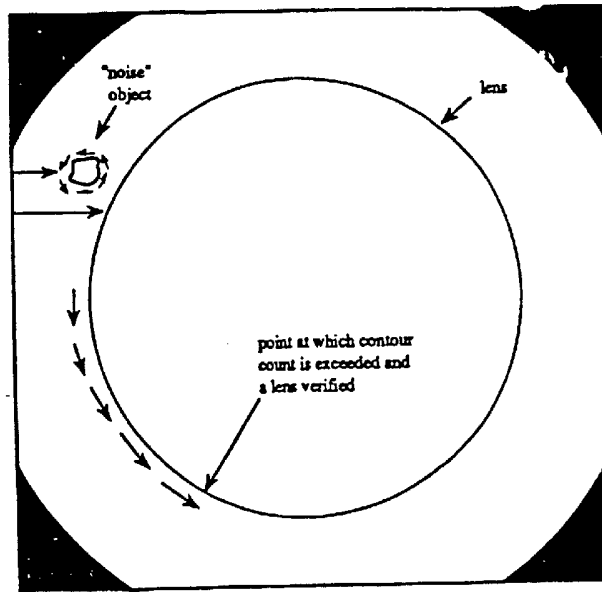


Fig. 17A

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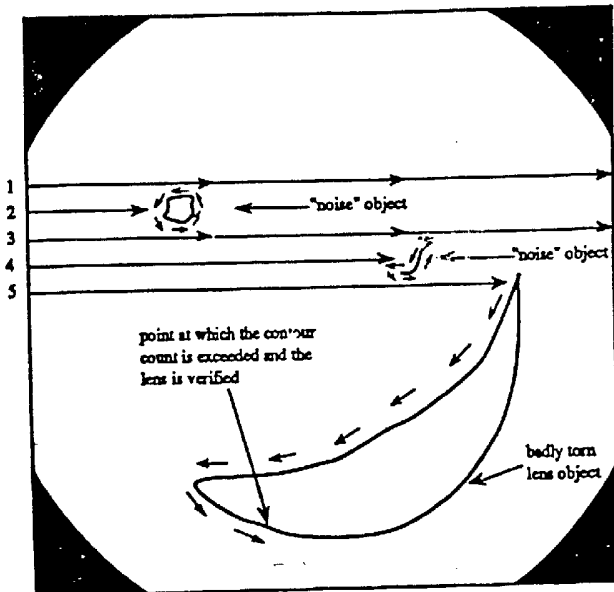


Fig. 17B

14/25

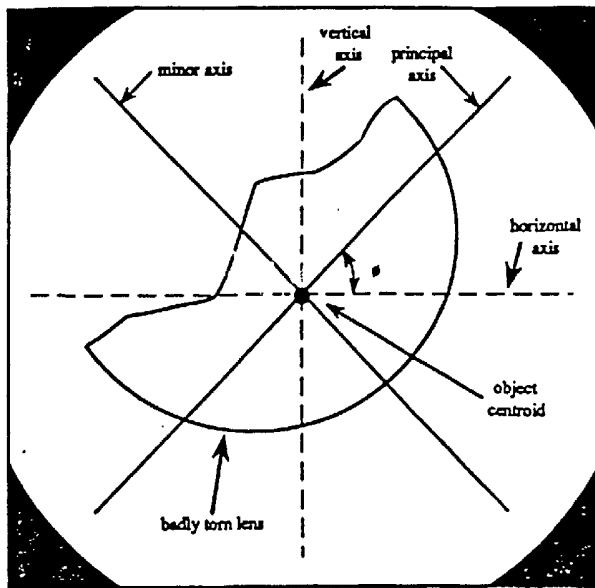


Fig. 18

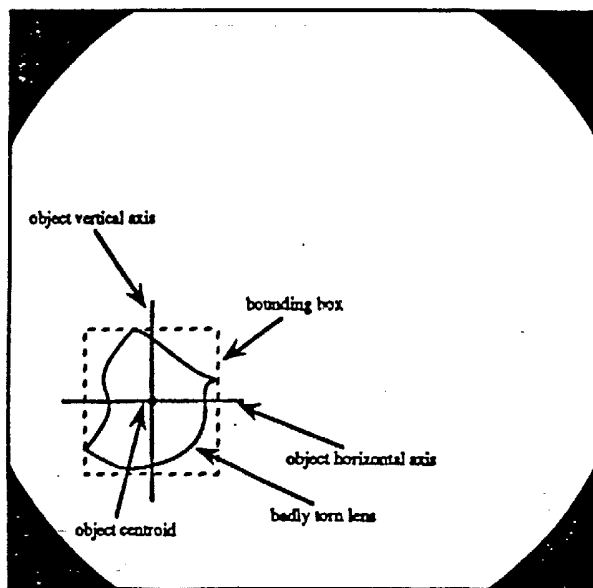


Fig. 19

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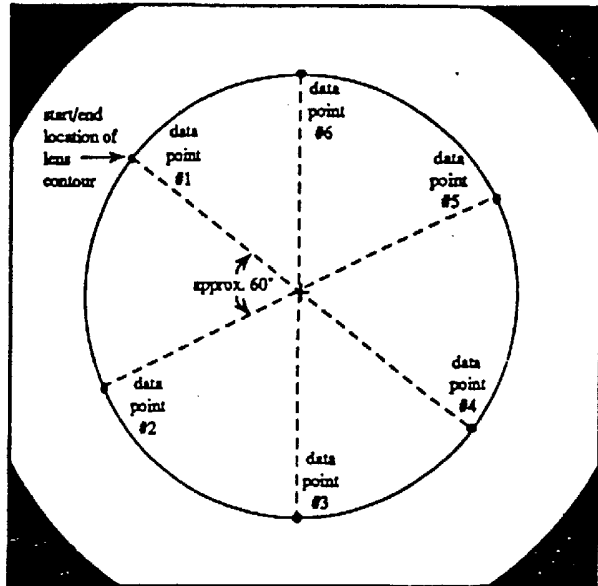


Fig. 20

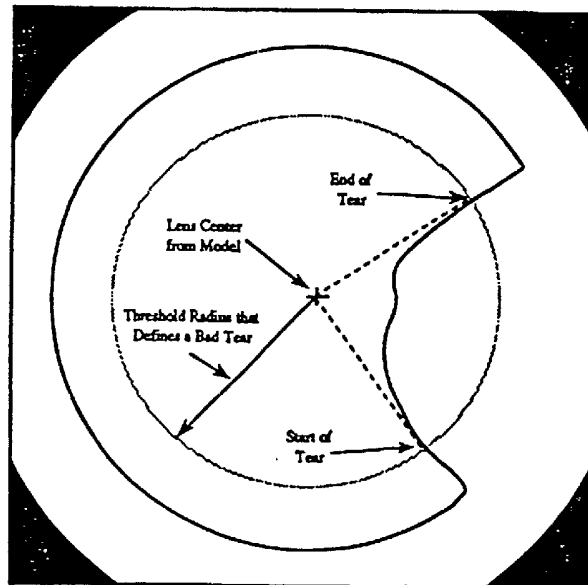


Fig. 21

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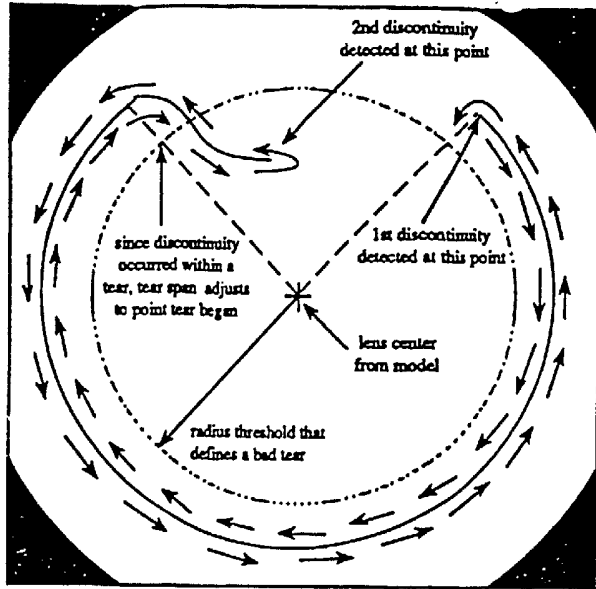


Fig. 22

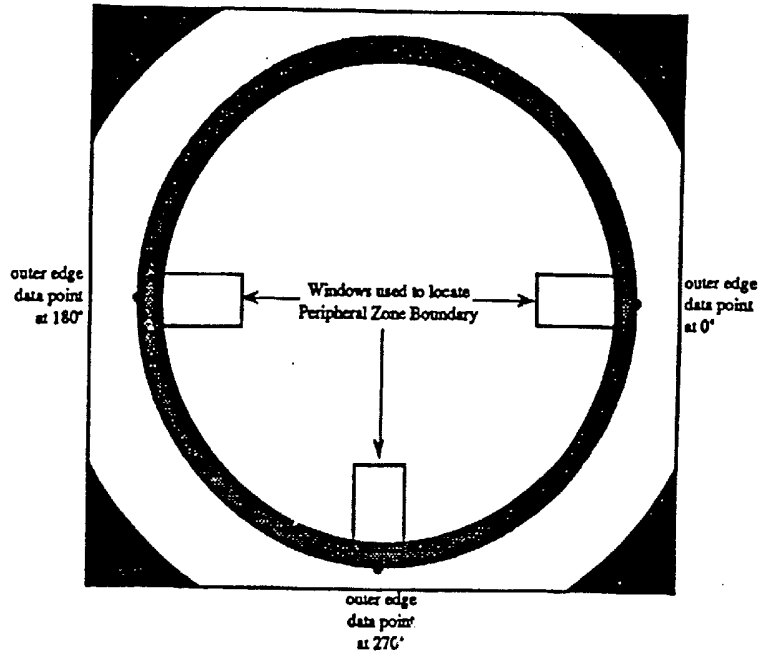


Fig. 23

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	1	2	3	4	5	6	7	8	9	10	11
1	-1	-1	-1	-1	-1	0	1	1	1	1	1
2	-2	-2	-2	-2	-2	0	2	2	2	2	2
3	-2	-2	-2	-2	-2	0	2	2	2	2	2
4	-2	-2	-2	-2	-2	0	2	2	2	2	2
5	-4	-4	-4	-4	-4	0	4	4	4	4	4
6	-4	-4	-4	-4	-4	0	4	4	4	4	4
7	-4	-4	-4	-4	-4	0	4	4	4	4	4
8	-2	-2	-2	-2	-2	0	2	2	2	2	2
9	-2	-2	-2	-2	-2	0	2	2	2	2	2
10	-2	-2	-2	-2	-2	0	2	2	2	2	2
11	-1	-1	-1	-1	-1	0	1	1	1	1	1

Fig. 24

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	1	2	3	4	5	6	7	8	9	10	11
1	-1	-2	-2	-2	-4	-4	-4	-2	-2	-2	-1
2	-1	-2	-2	-2	-4	-4	-4	-2	-2	-2	-1
3	-1	-2	-2	-2	-4	-4	-4	-2	-2	-2	-1
4	-1	-2	-2	-2	-4	-4	-4	-2	-2	-2	-1
5	-1	-2	-2	-2	-4	-4	-4	-2	-2	-2	-1
6	0	0	0	0	0	0	0	0	0	0	0
7	1	2	2	2	4	4	4	2	2	2	1
8	1	2	2	2	4	4	4	2	2	2	1
9	1	2	2	2	4	4	4	2	2	2	1
10	1	2	2	2	4	4	4	2	2	2	1
11	1	2	2	2	4	4	4	2	2	2	1

Fig. 25

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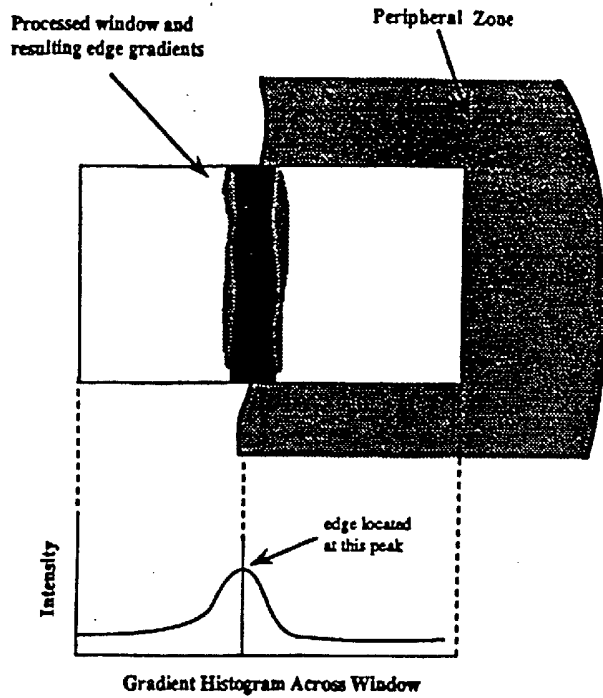


Fig. 26

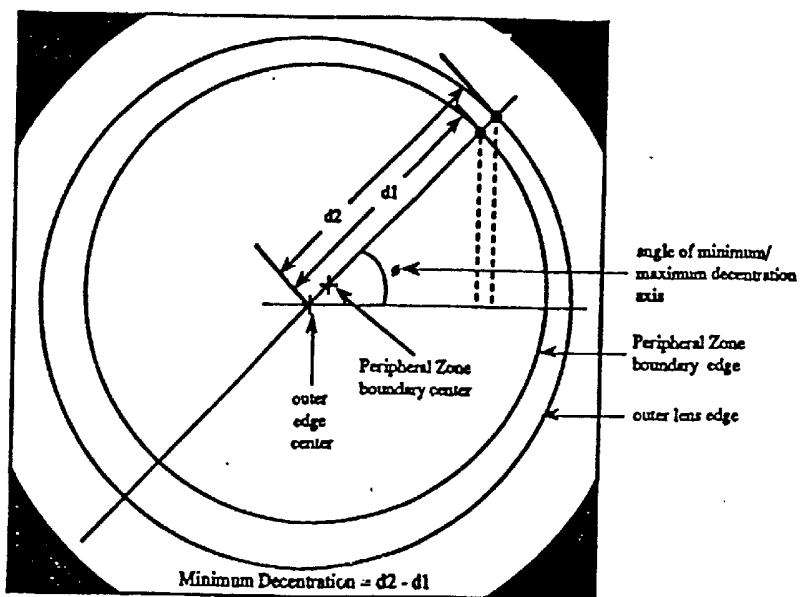


Fig. 27

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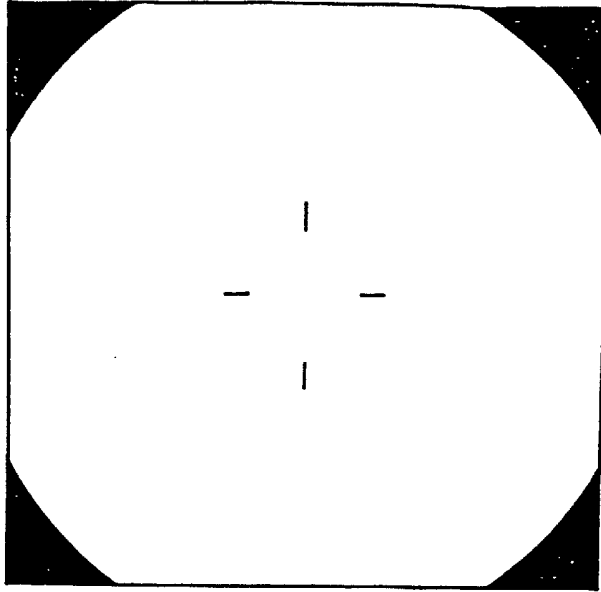


Fig. 28

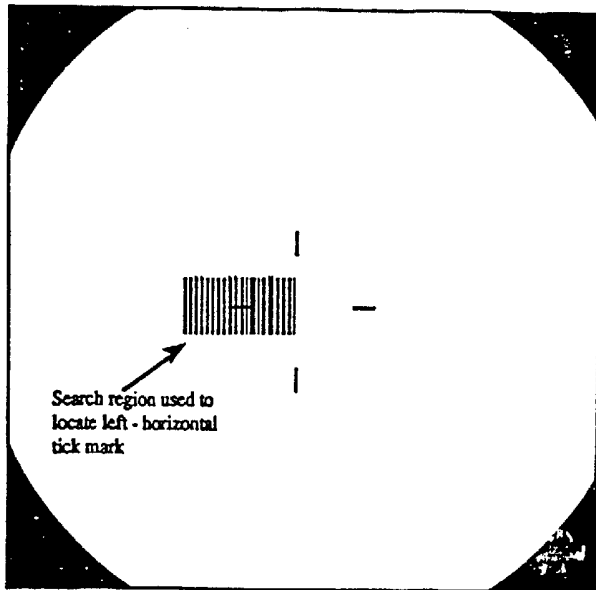


Fig. 29

7
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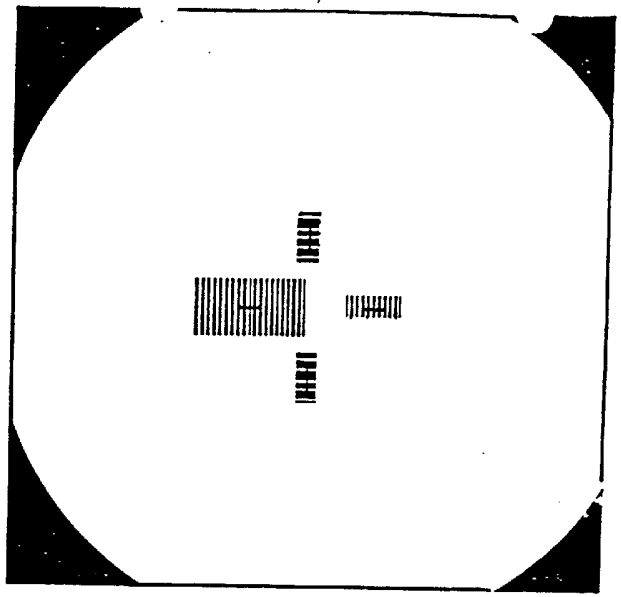


Fig. 30

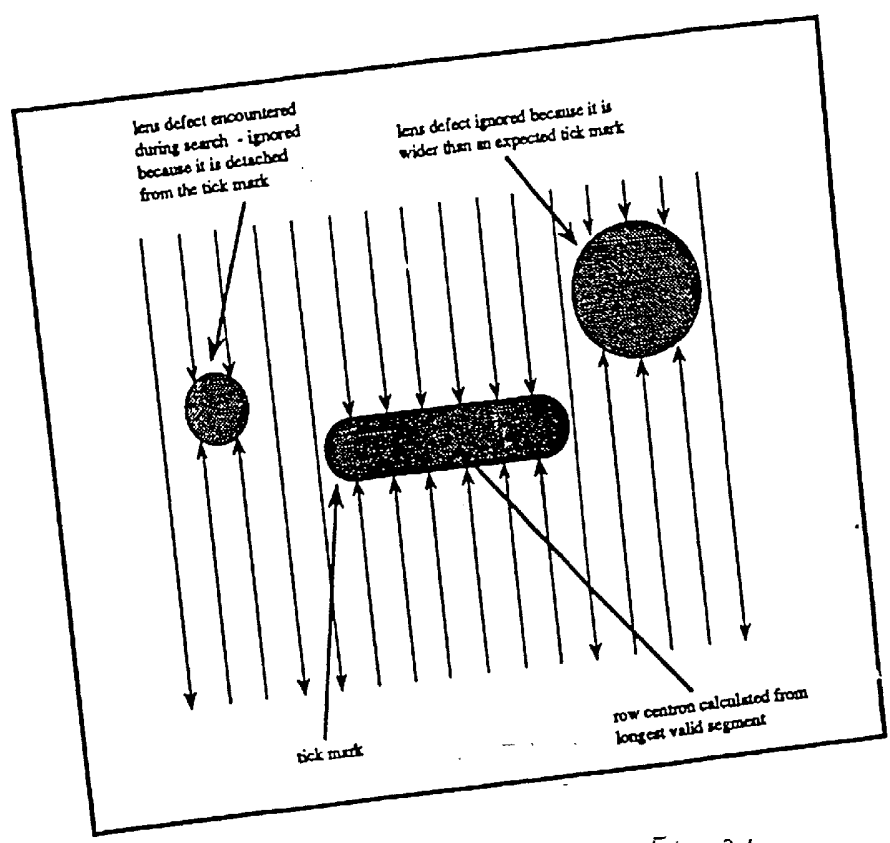


Fig. 31

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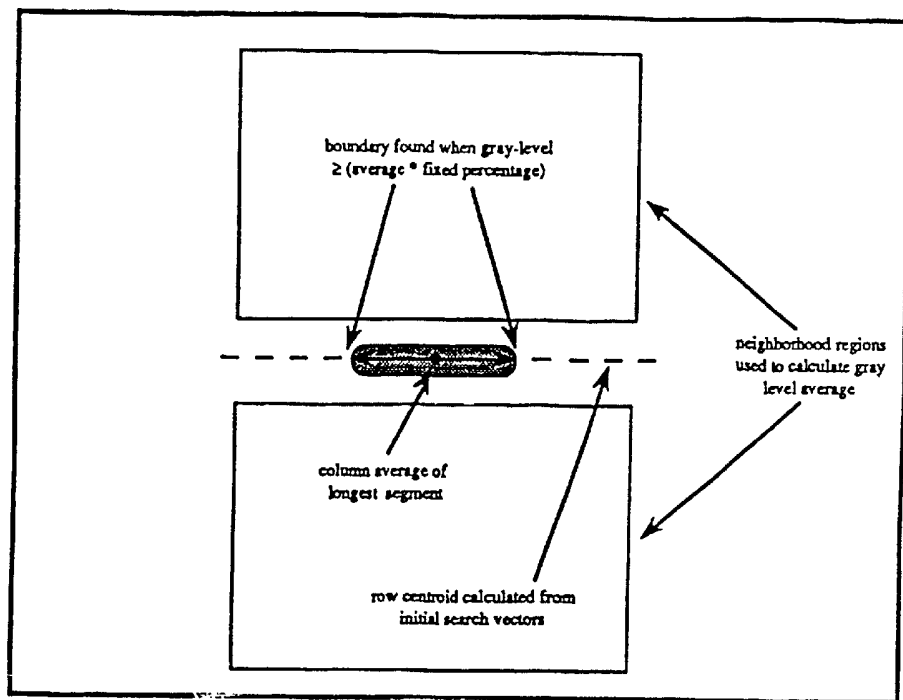


Fig. 32

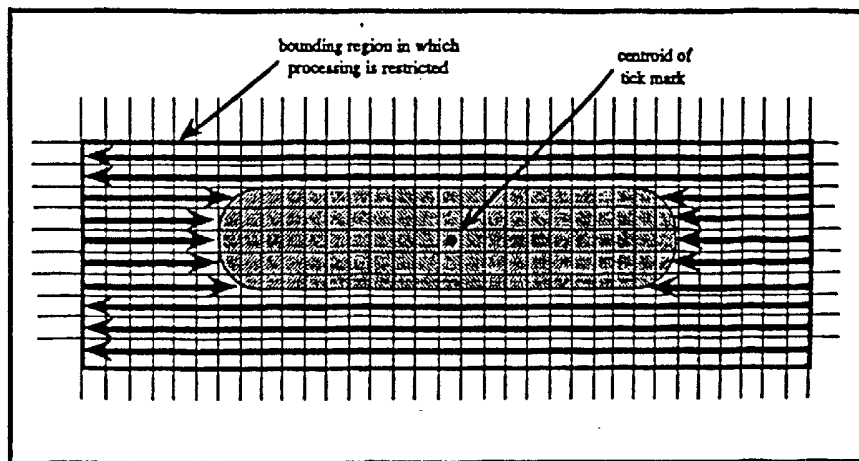


Fig. 33

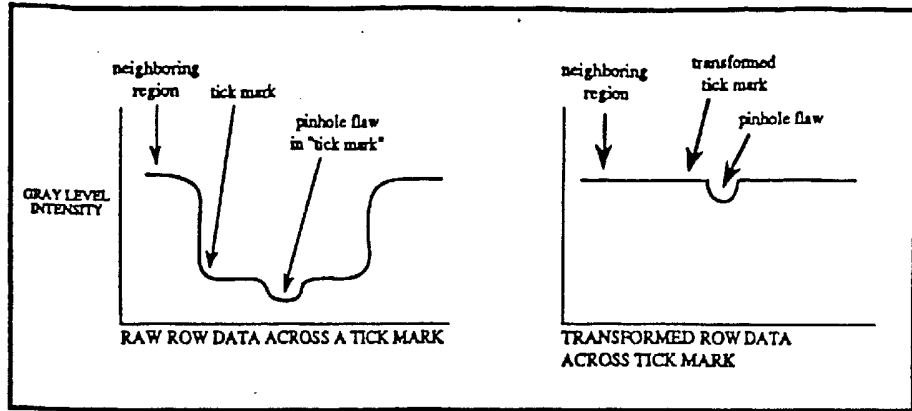


Fig. 34

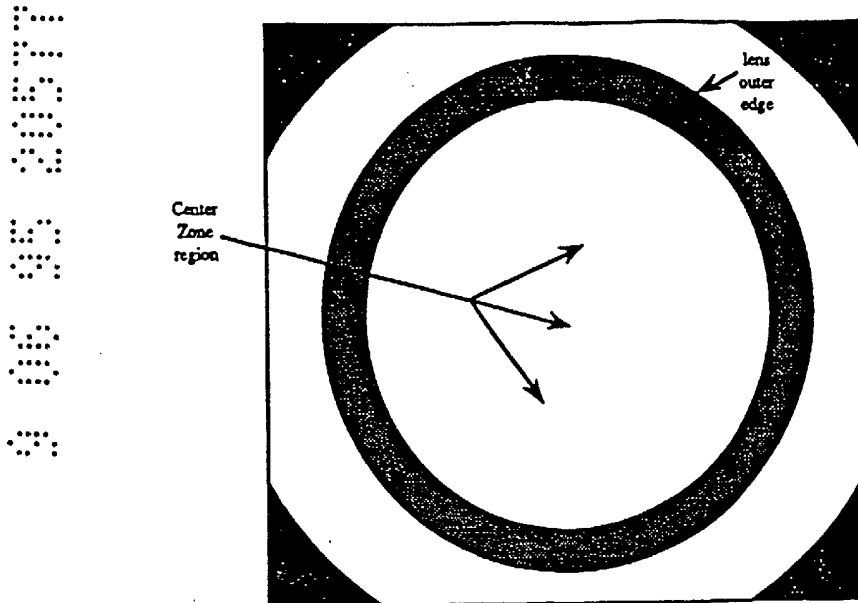
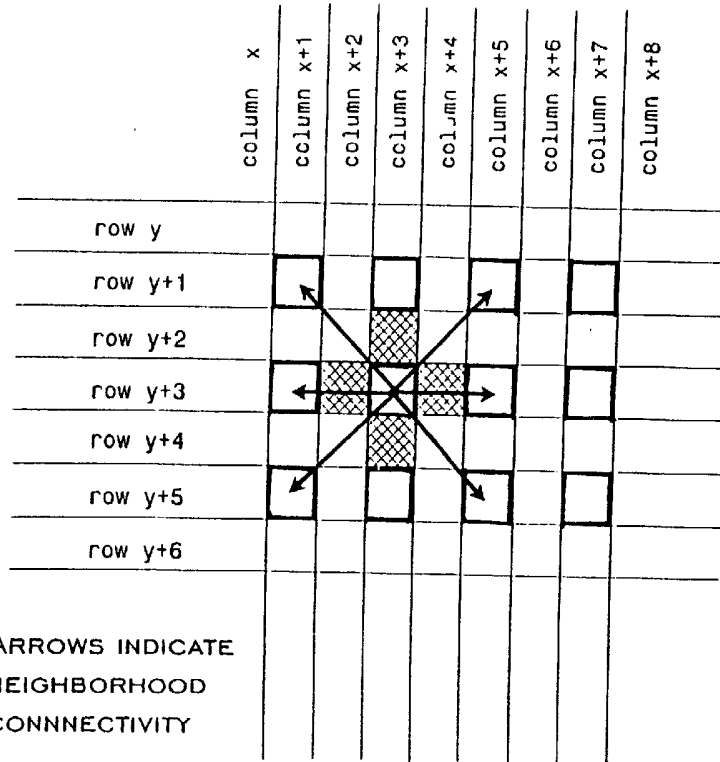


Fig. 35

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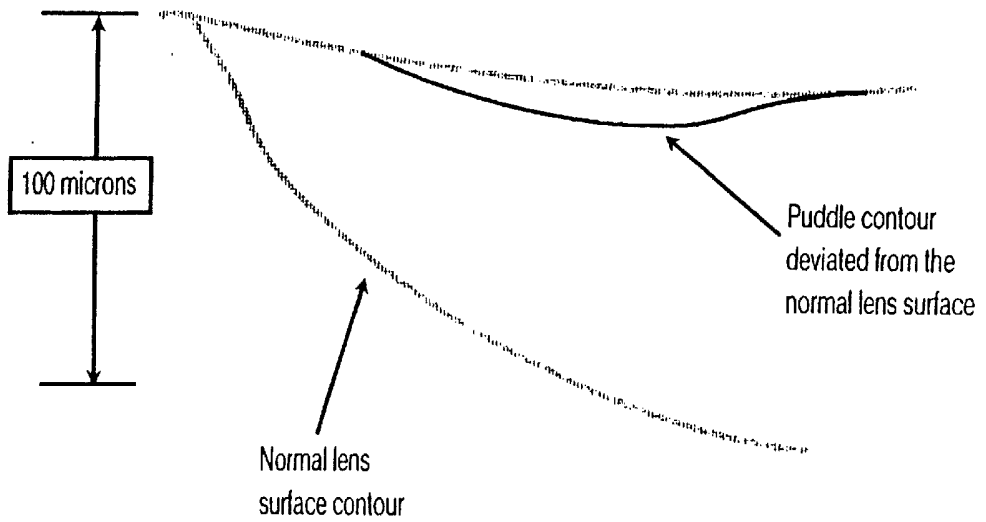
ARROWS INDICATE
NEIGHBORHOOD
CONNECTIVITY

□ = pixel used in subsampled pattern □ (cross-hatched) = pixel used in gradient calculations

Subsampling Pattern in Center Zone

Fig. 36

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Typical Puddle Cross Section

Fig. 37

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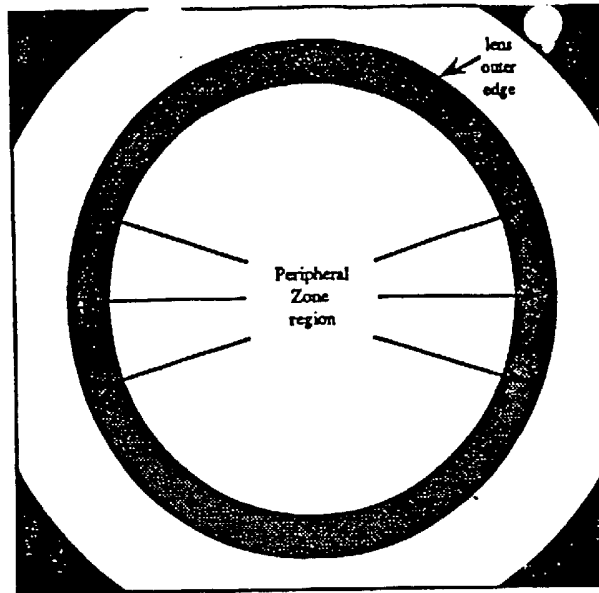


Fig. 38

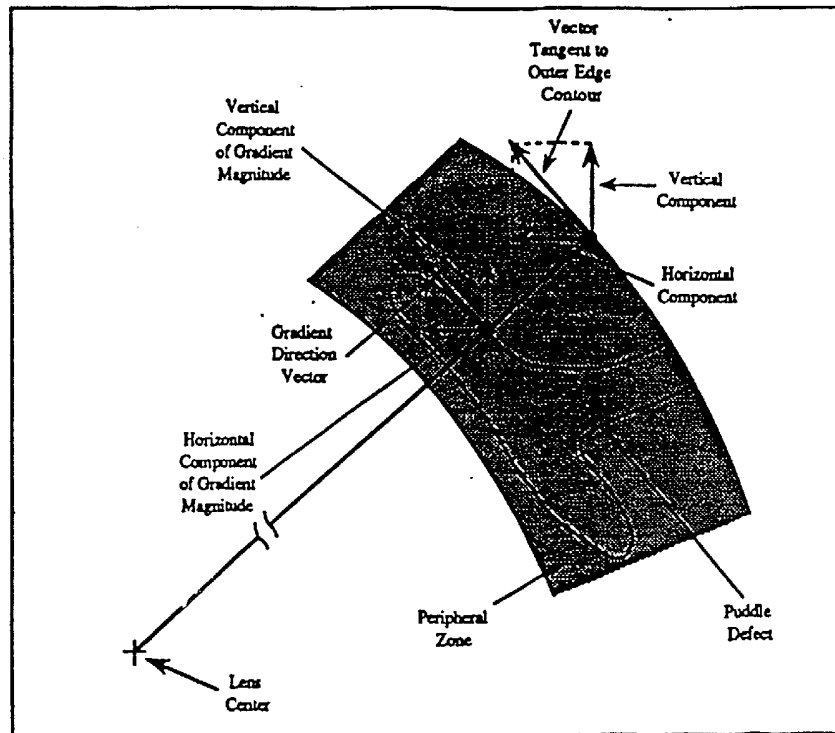


Fig. 39